



Development and test of new technologies for manufacturing high purity germanium segmented detector

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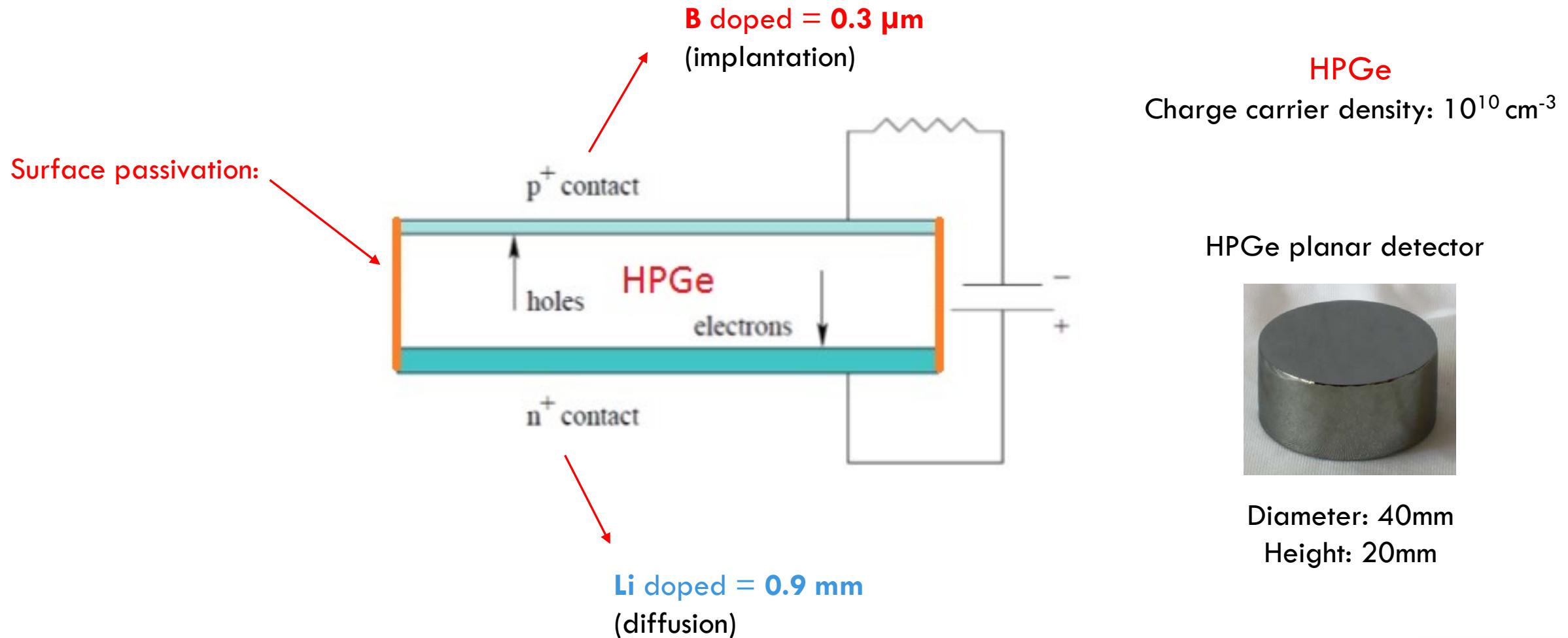
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OUTLINE

- Introduction: HPGe gamma detectors
- Gamma detector state of the art
- *PLM (Pulse Laser Melting)*: Next generation of segmented contact/junction on HPGe detectors
- PLM Planar gamma segmented detectors
- PLM Coxial gamma segmented detectors
- Neutron damage in PLM planar segmented detectors

Schematic HPGe planar gamma detector



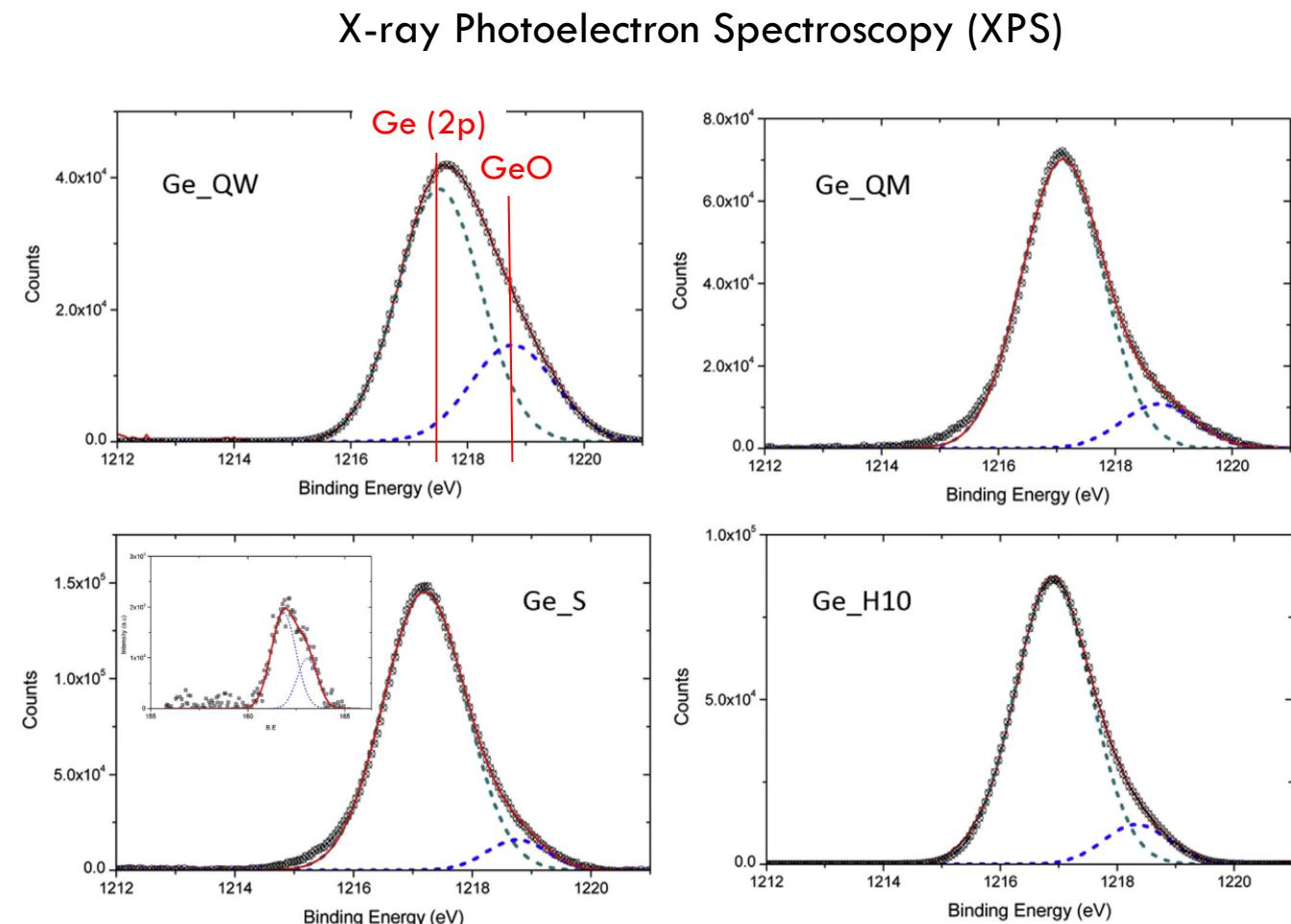
HPGe gamma detector (*chemical Passivation*)

Passivation techniques: study the evolution
of Ge – GeO – GeO₂



HNO₃/HF (3:1) etching and quenching bath:

- Water (Ge_W)
- Methanol (Ge_QM)
- Sulfide termination (Ge_S)
- Hydride termination (Ge_H10)



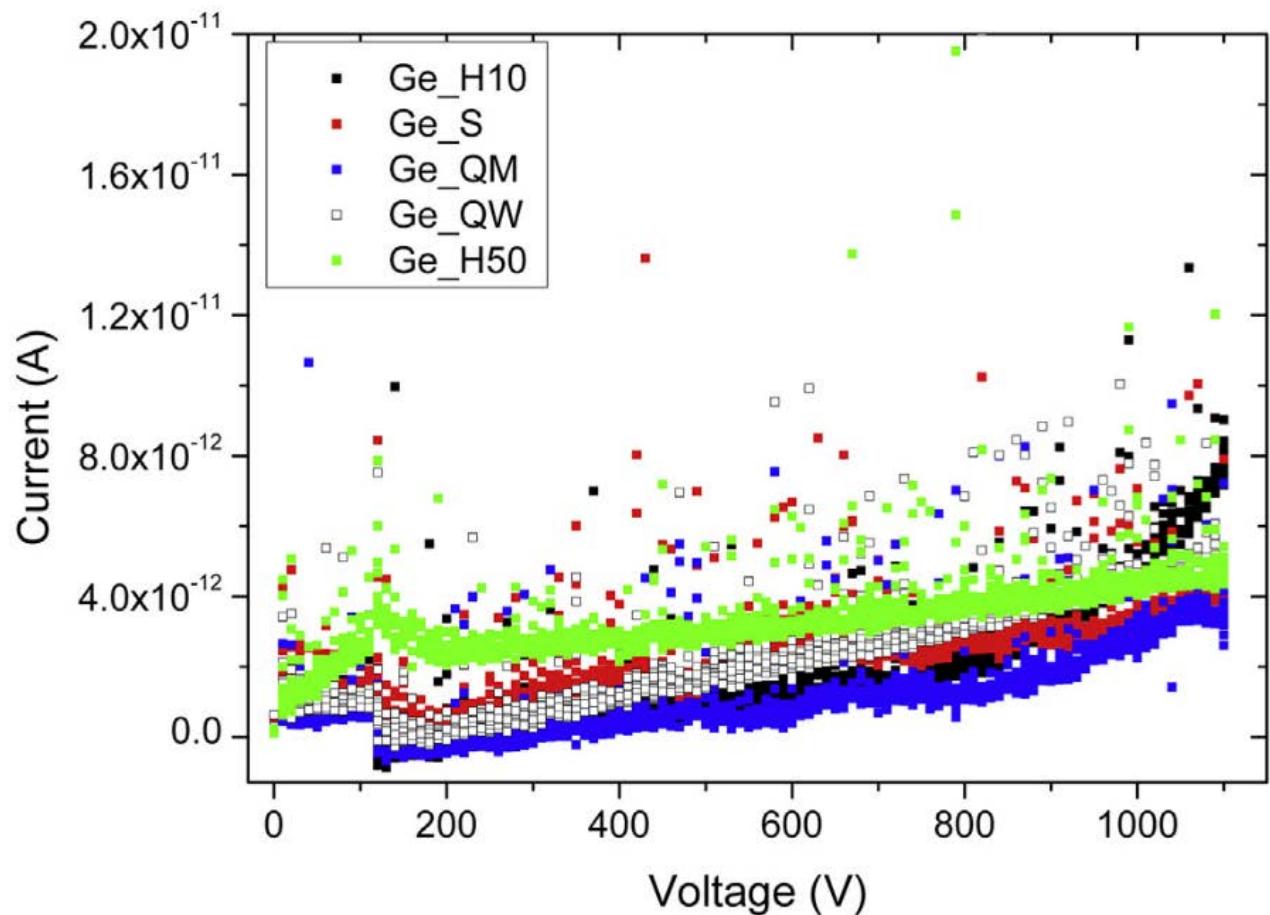
National Laboratories of Legnaro (LNL)
University of Padua (UNIPD)
& IKP Cologne

S. Carturan et al., Mater. Chem. Phys. 2015

HPGe gamma detector (*Passivation test*)

I-V Curve to determine the leakage current
(in diode configuration measurements at cryogenic temperature)

- Crystal is depleted (reverse bias)
- Crystal at 80 ÷ 90K



S. Carturan et al., Mater. Chem. Phys. 2015

OUTLINE

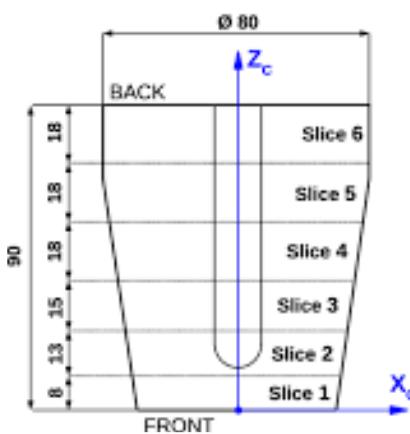
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Gamma detector state of the art (AGATA)

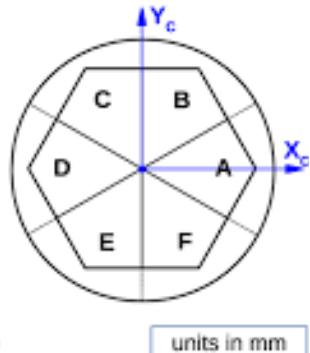
Encapsulated coaxial HPGe n-type detectors



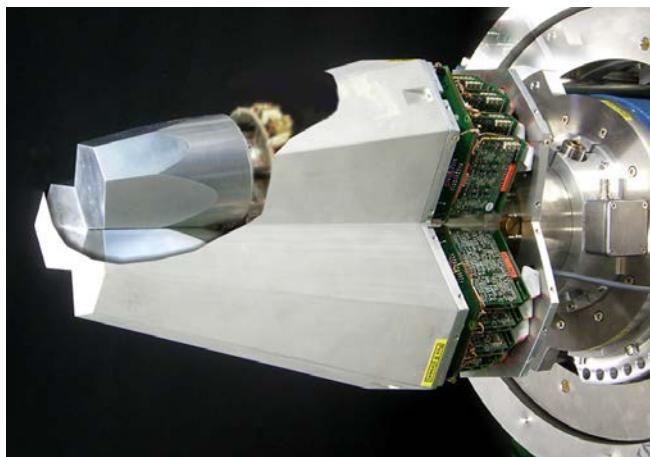
LATERAL VIEW



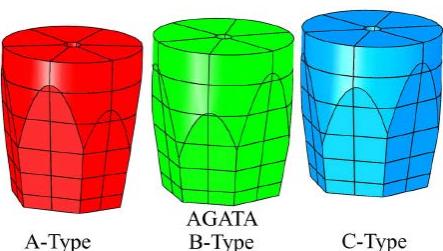
FRONTAL VIEW



ATC (AGATA triple cluster detector)



3 asymmetrical HPGe detector



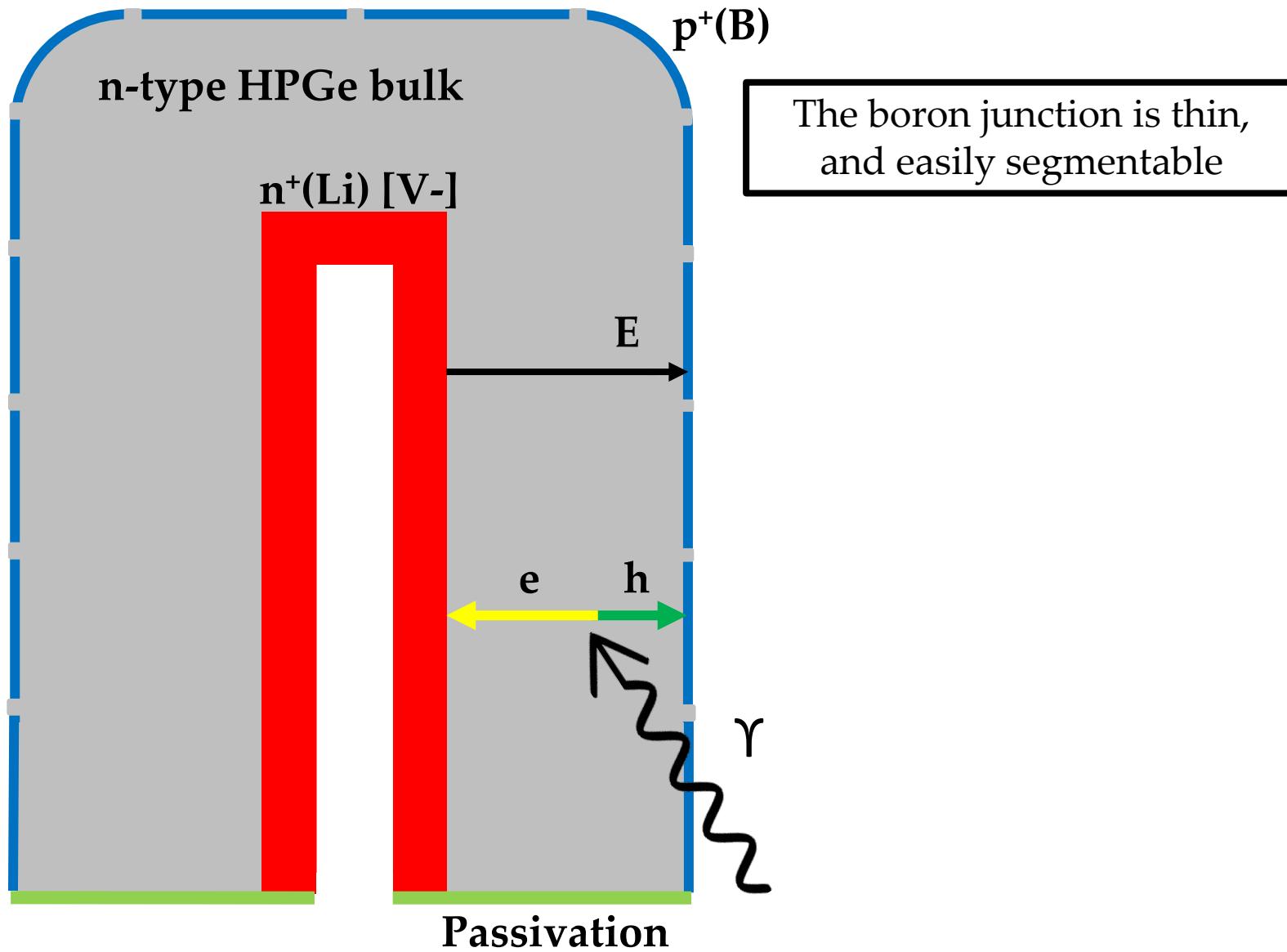
J. Eberth et al. **Eur. Phys. J. A** (2023) 59: 179

Installation at LNL-INFN (13ATCs)

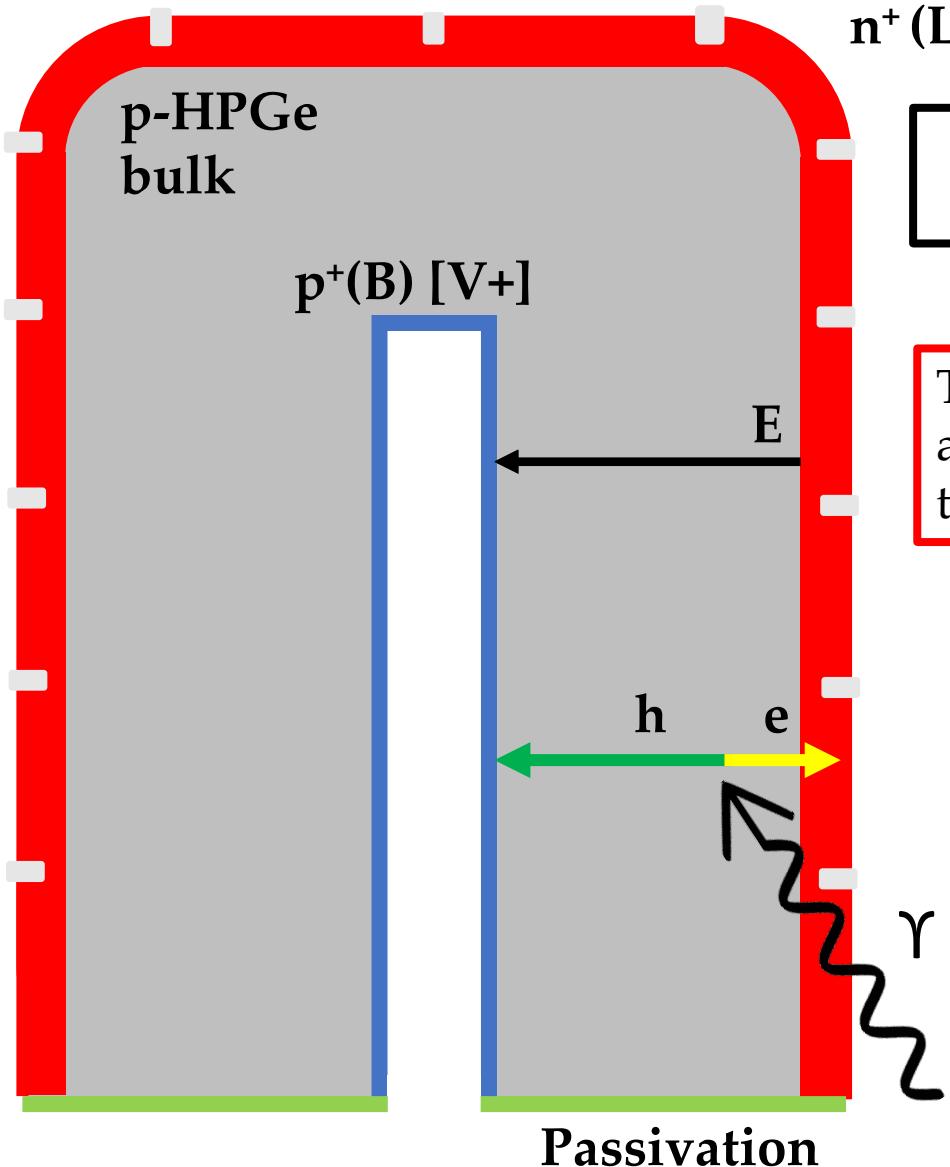


J.J Valiente al. **NIM Phys. Res. A** (2023) 1049

Schematic coaxial segmented *n*-type detector



Schematic coaxial segmented p-type detector



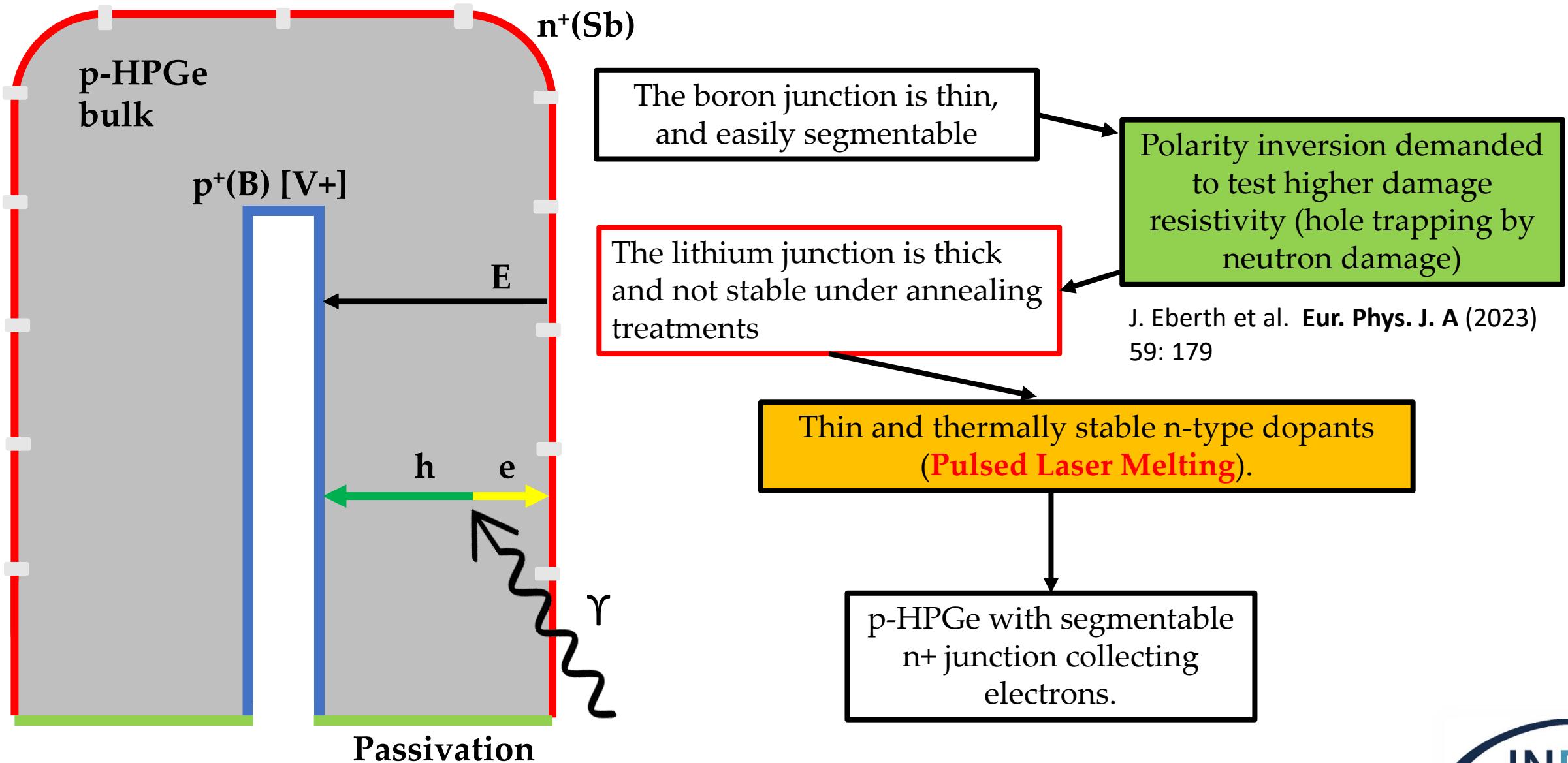
The boron junction is thin,
and easily segmentable

The lithium junction is thick
and not stable under annealing
treatments

Polarity inversion demanded
to test higher damage
resistivity (hole trapping by
neutron damage)

J. Eberth et al. *Eur. Phys. J. A* (2023)
59: 179

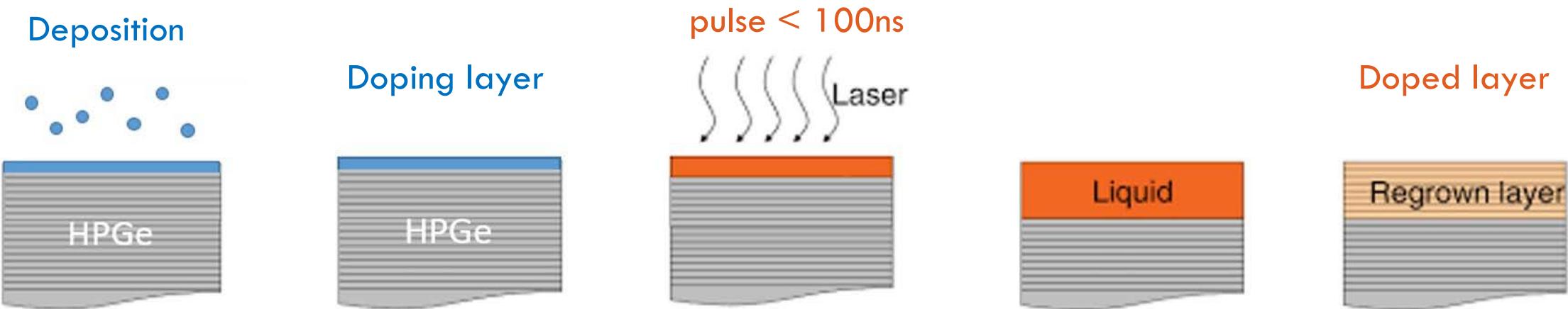
Schematic coaxial segmented p-type detector



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New contact/junction on HPGe: PLM (Pulse Laser Melting)



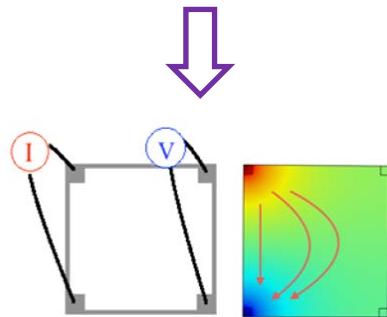
Advantages:

- Melting temperature is reached - short time (< 100 ns)
- Only the surface (< 200 nm) is melted, the bulk is at room temperature
- High dopant concentrations with very sharp dopant profile
- Doping with heavy elements without crystal damage
- Very clean process suitable for preserving the Ge hyperpurity
- Suitable for complex contact geometries (**segmentation**)

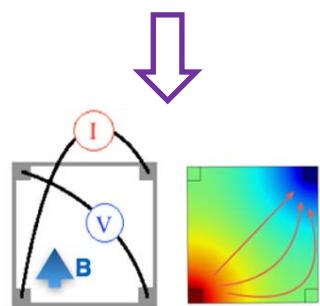
New contact/junction on HPGe: PLM on HPGe crystal



Van Der Pauw



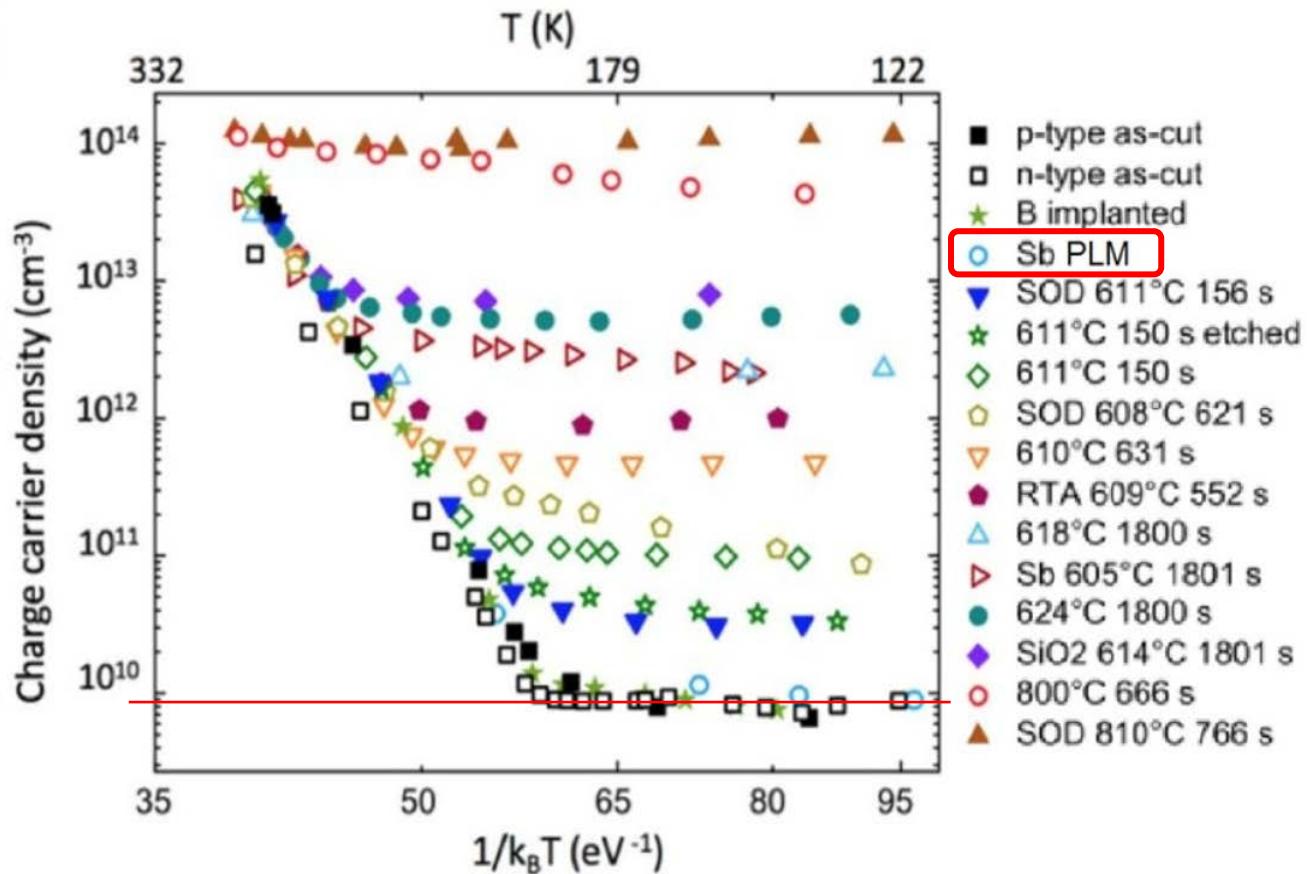
Hall



Impurities concentration in Ge bulk

Sheet resistance

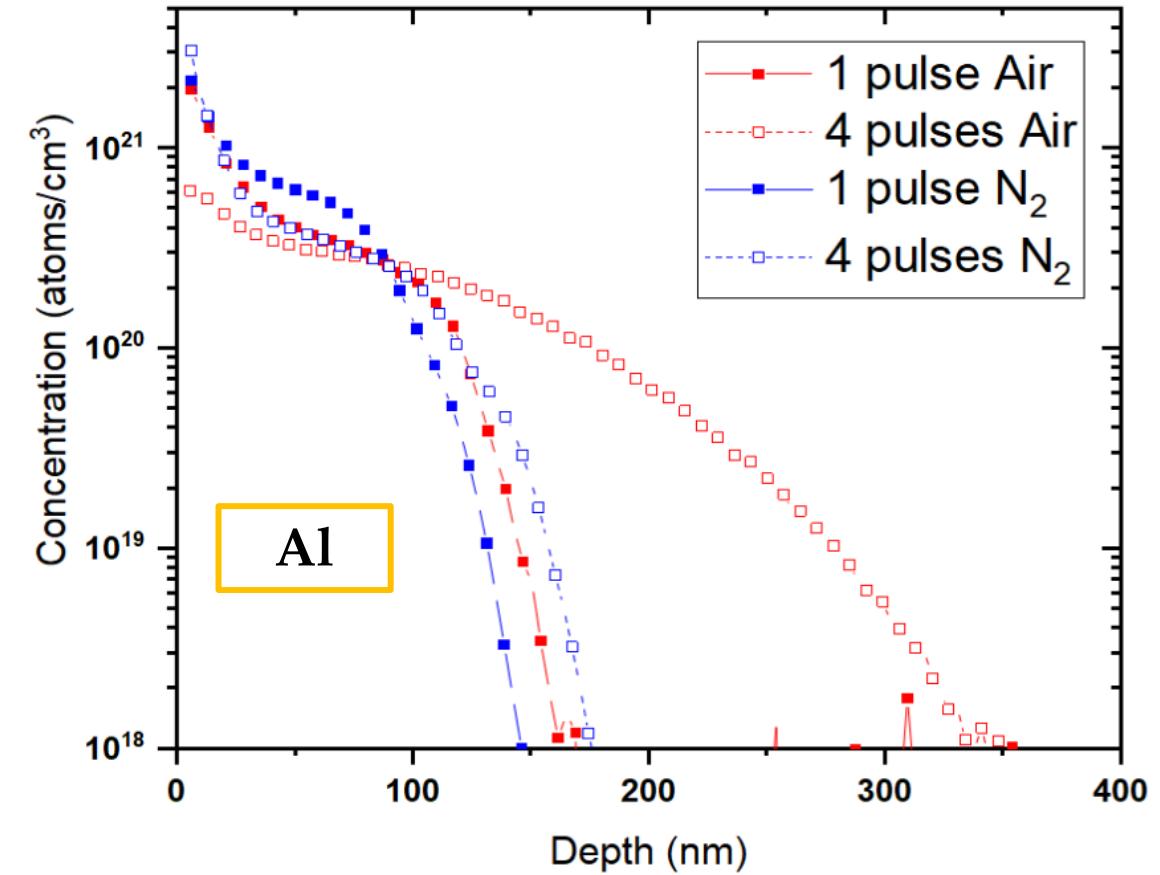
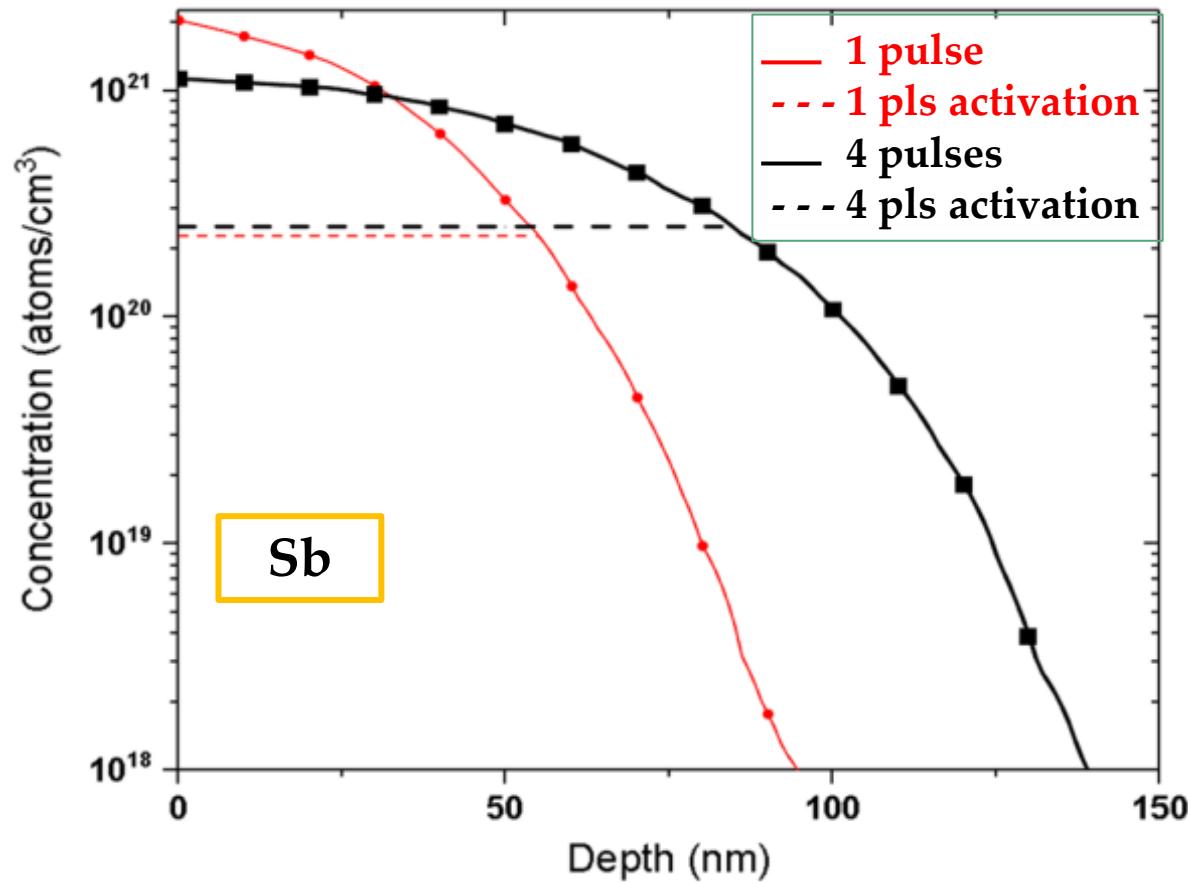
Charge carriers



V. Boldrini et al., *Journal of Physics D: Applied Physics* (2018) volume 52, 3

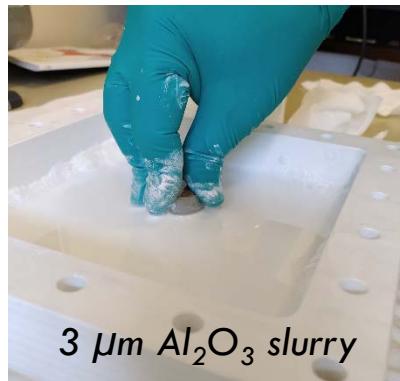
New contact/junction on HPGe: Chemical concentration profile

SIMS (Secondary Ions Mass Spectrometry)



New contact/junction on HPGe: Surface preparation

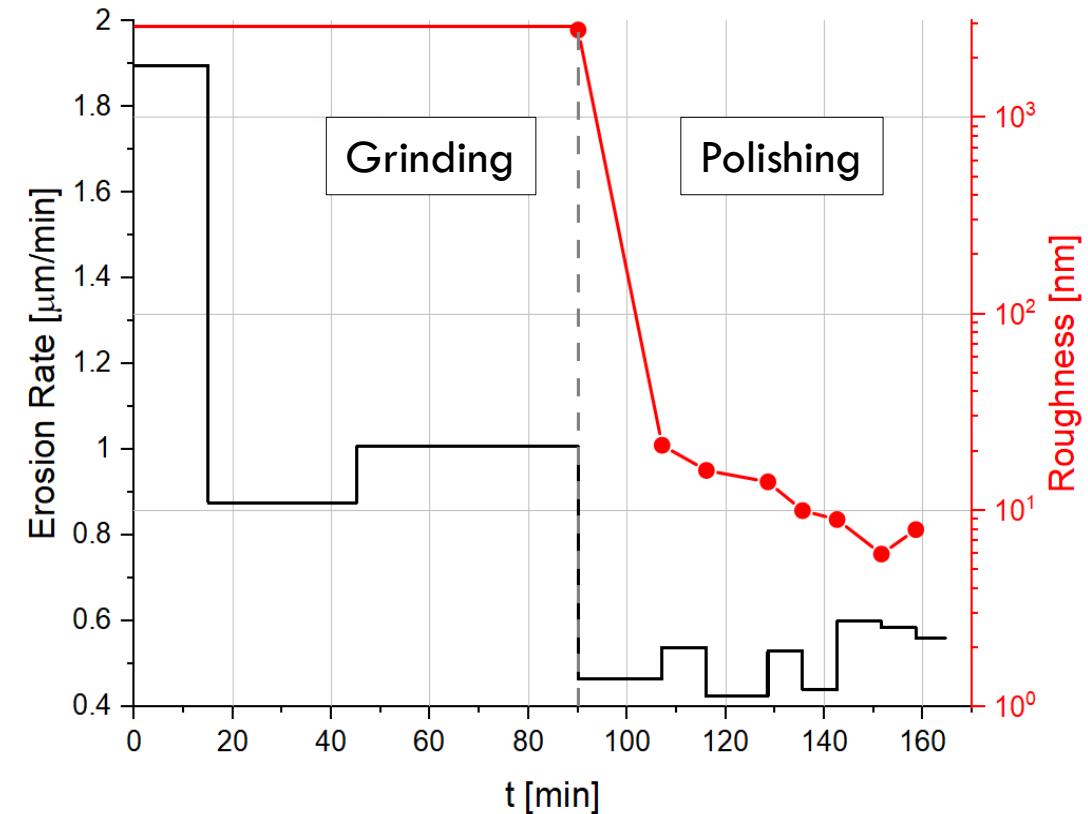
Grinded surface



Etched surface
(High waviness,
low roughness)

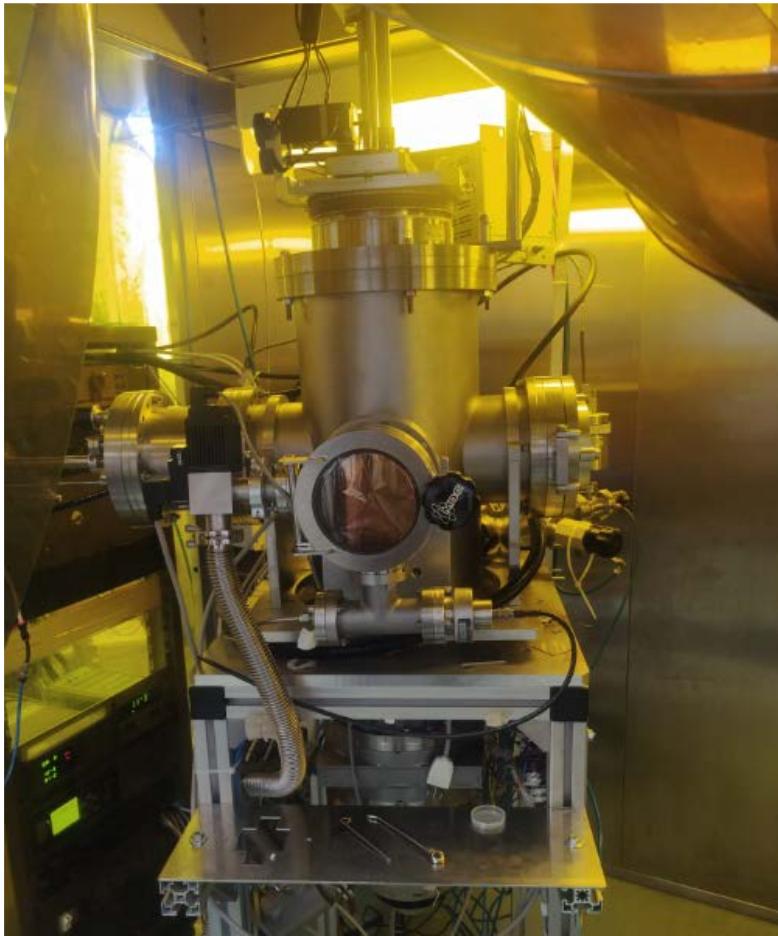


Polished surface
(Low waviness,
low roughness)

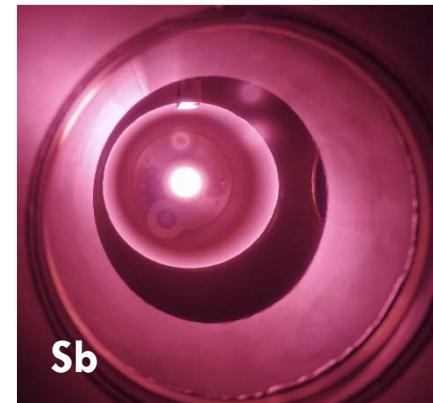


New contact/junction on HPGe: PVD Sputtering deposition

Magnetron Sputtering deposition



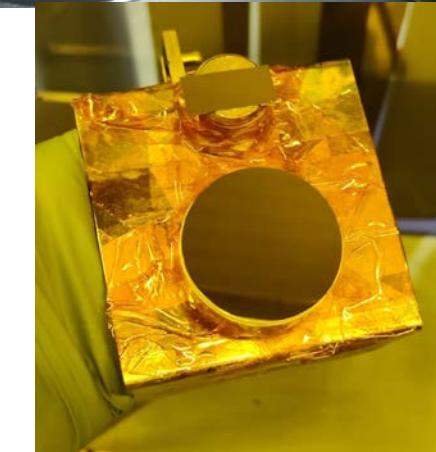
Sb material



Al / Ge material

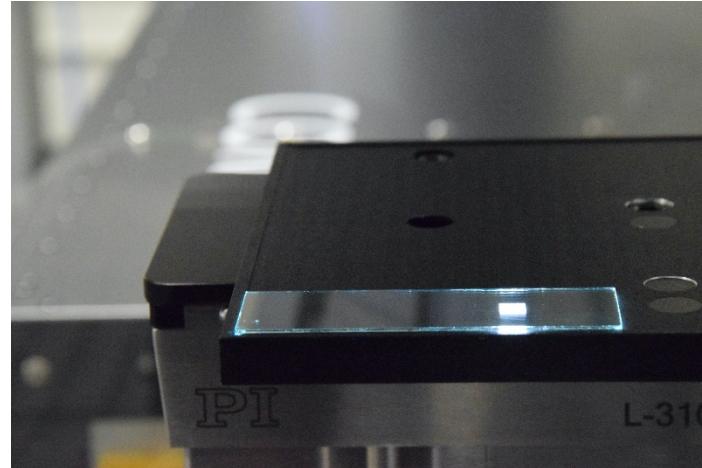
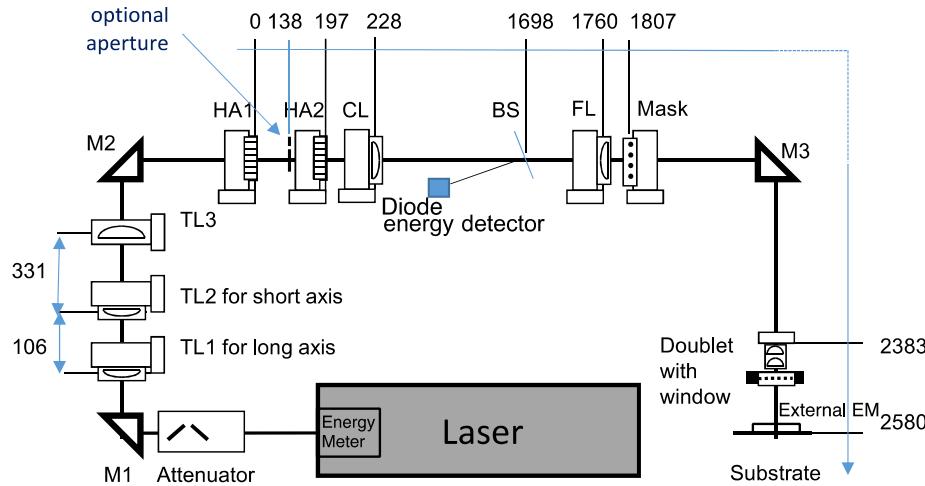


n^+	Sb	2 nm
p^+	Al (Ge cap)	4 nm (10 nm)

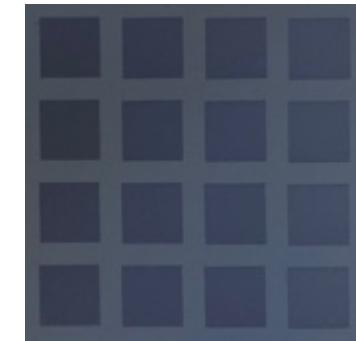


New contact/junction on HPGe: PLM Laser technology

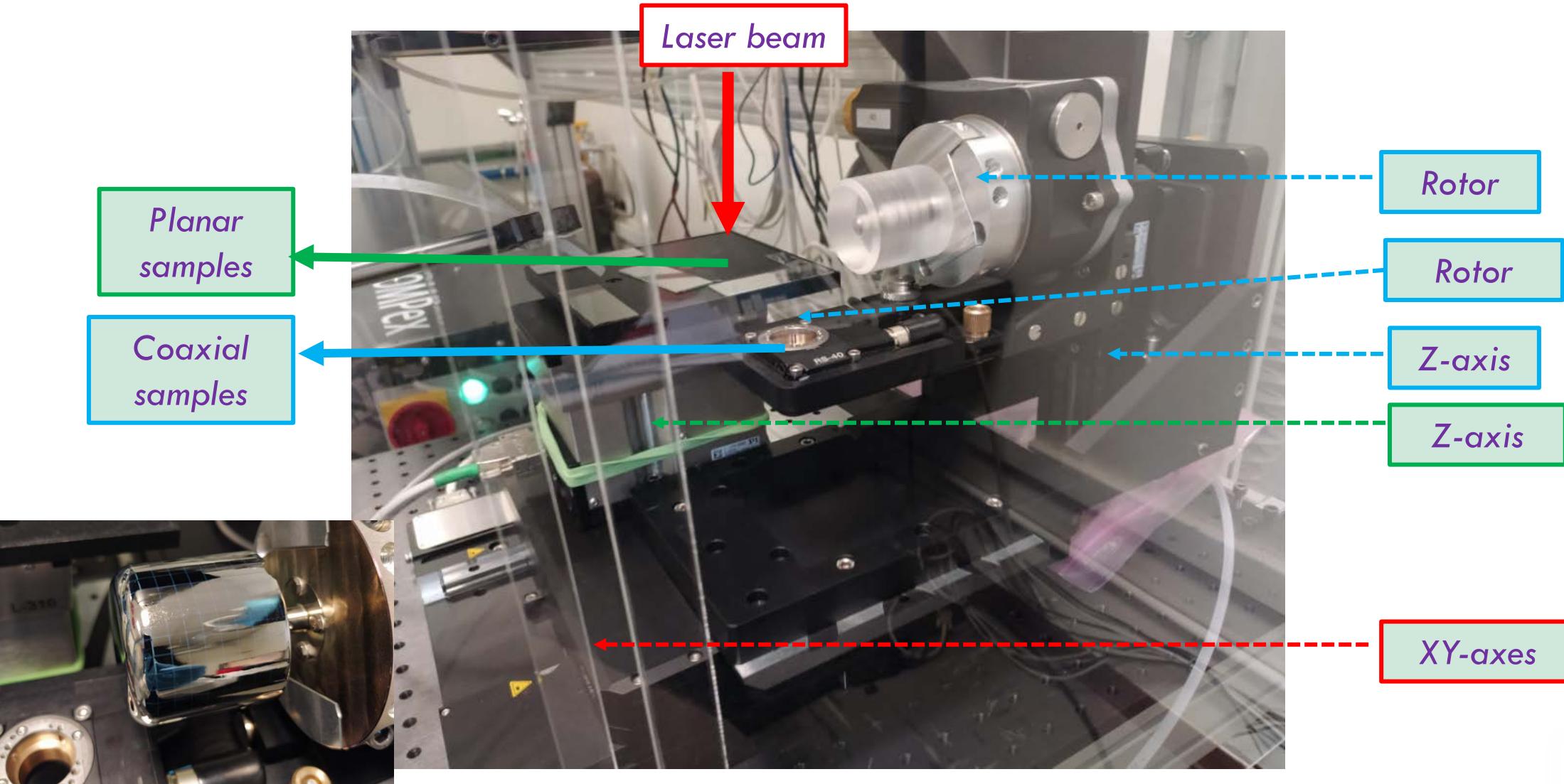
Excimer KrF laser



- $\lambda=248 \text{ nm}, 22 \text{ ns}$
- Frequency: 1-10 Hz
- ED= 50-1300 mJ/cm²
- Square 5x5mm² spot
- Homogeneity: < 2%
- lateral resolution <30 μm
- Motorized XYZ stage



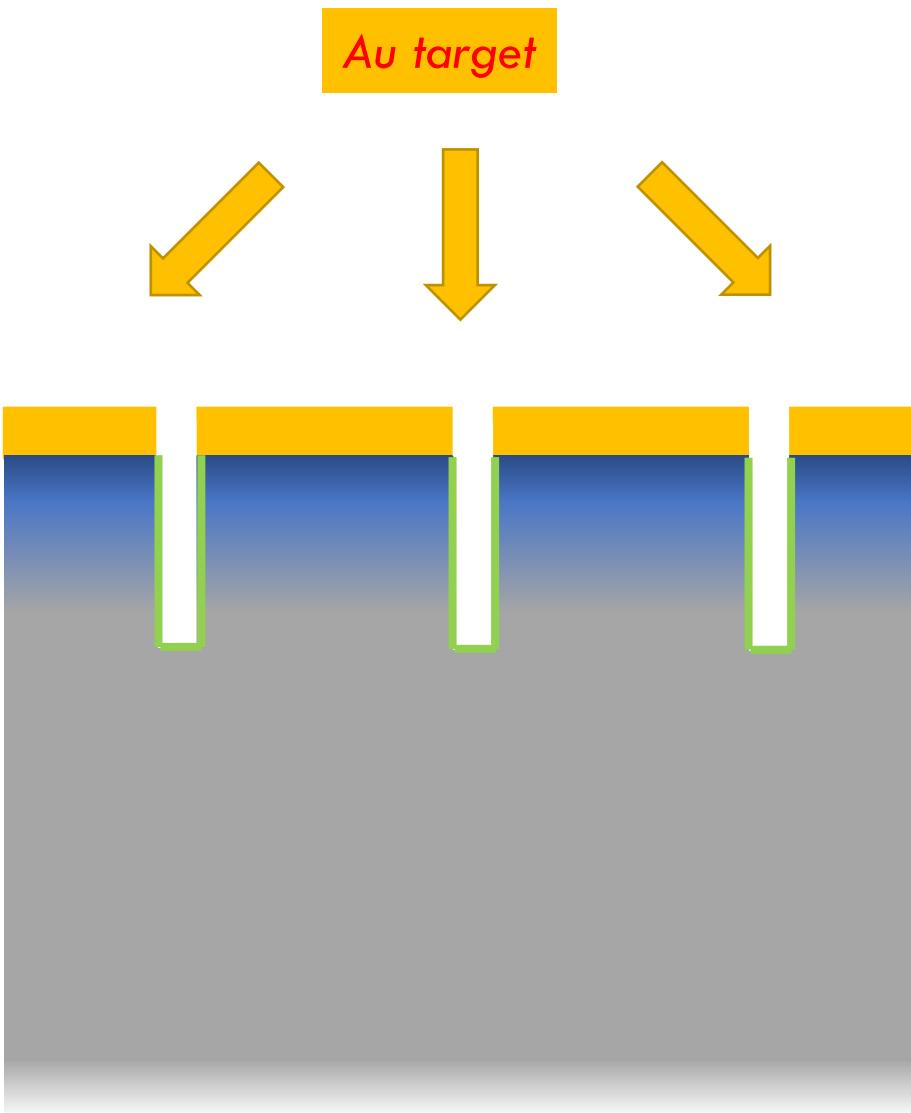
New contact/junction on HPGe: PLM Laser technology



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PLM contact/junction: 1° type Segmentation



Full area ← **PLM**



Au deposition

100 nm PVD deposition of Au in Ar plasma with ultrapure target in vacuum (10^{-6} mbar)



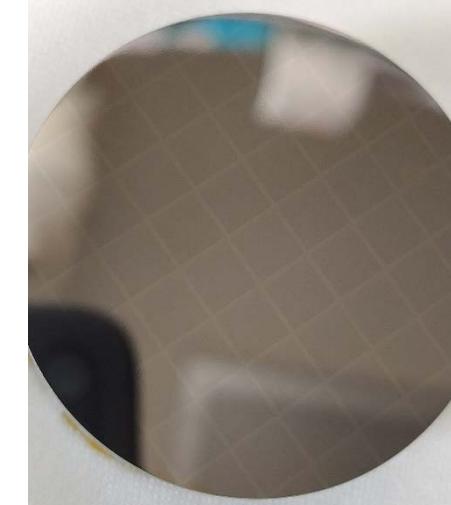
Photolithography

Photoresist deposition, baking, exposure and development, followed by Au stripping and resist removal.



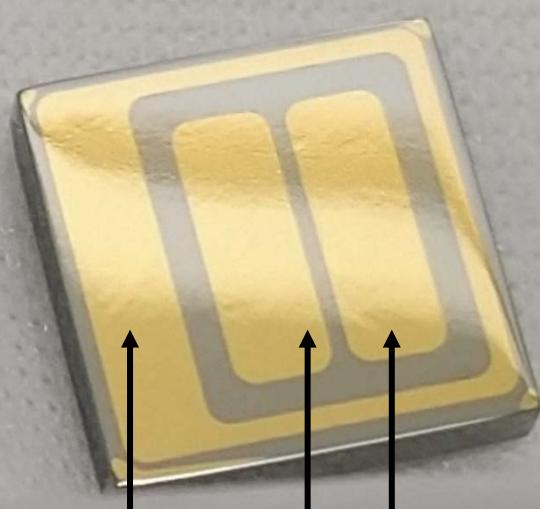
Intercontact gaps passivation

(3:1) HNO_3 : HF etching followed by chemical quenching passivation.



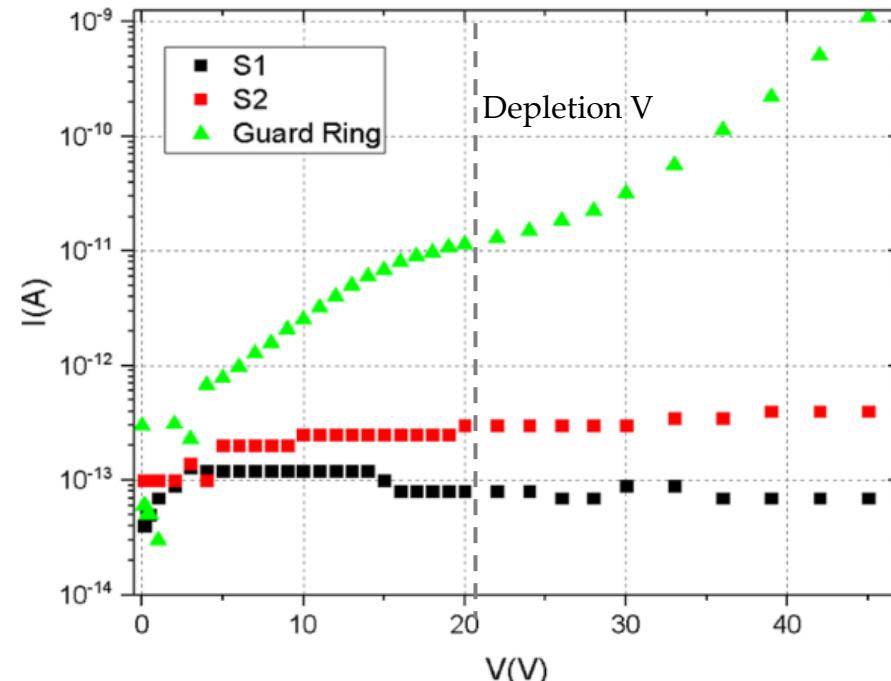
Thin planar HPGe detectors

Sb n⁺ junction, p-type HPGe,
B p⁺ L=10mm, t=2mm



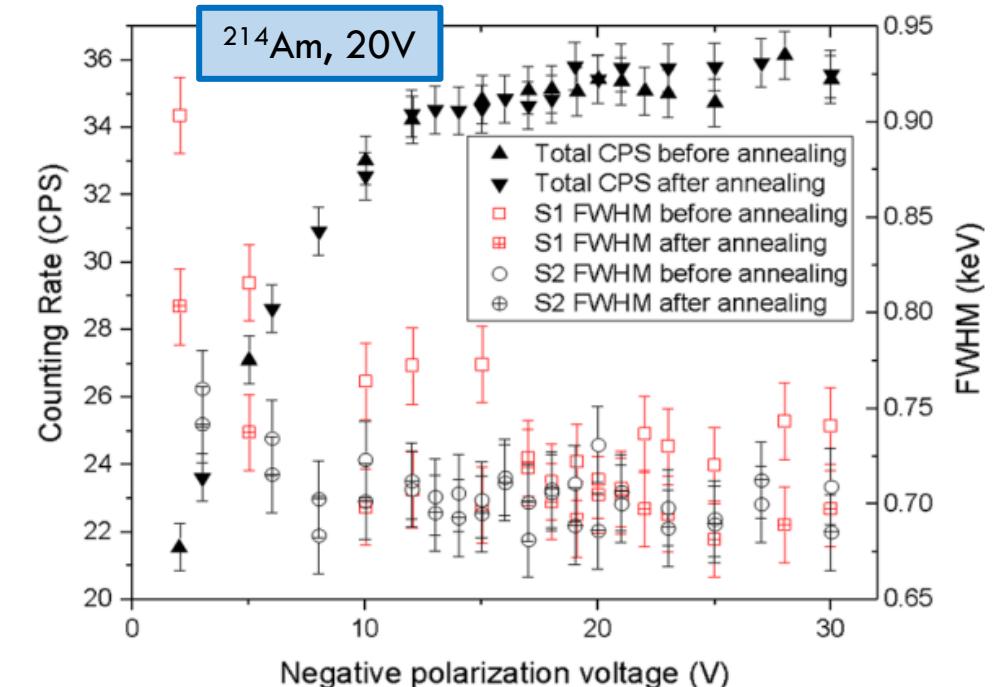
Measured before and
after recovery annealing
and re-passivation to test
junction stability

Electrical test:
reverse I-V characteristics



Gamma ray test:
241Am spectra acquisition

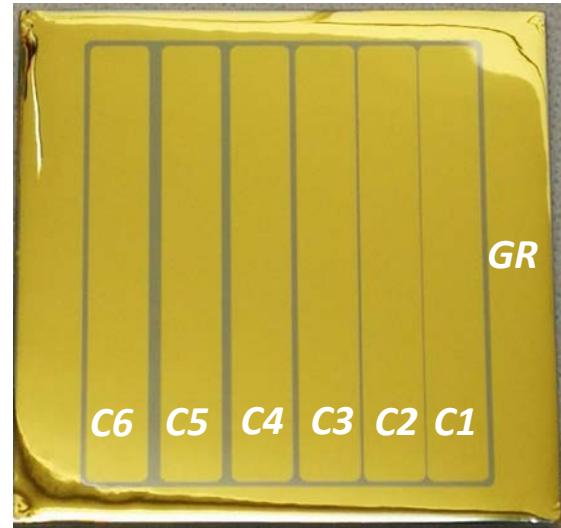
Annealing at 105°C



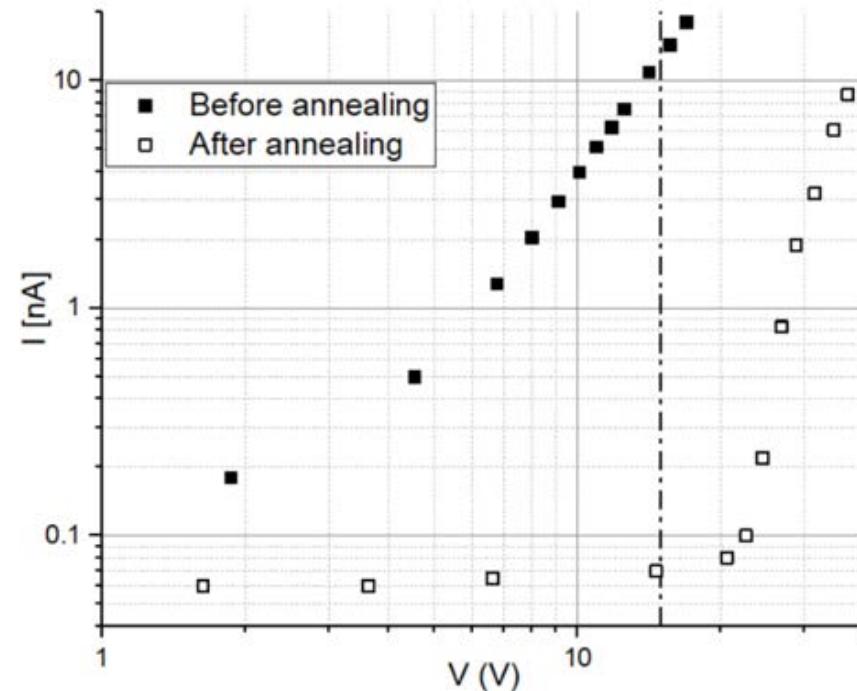
S. Bertoldo et al., Eur. Phys. J. A (2021) 57:177

Thin planar HPGe detectors

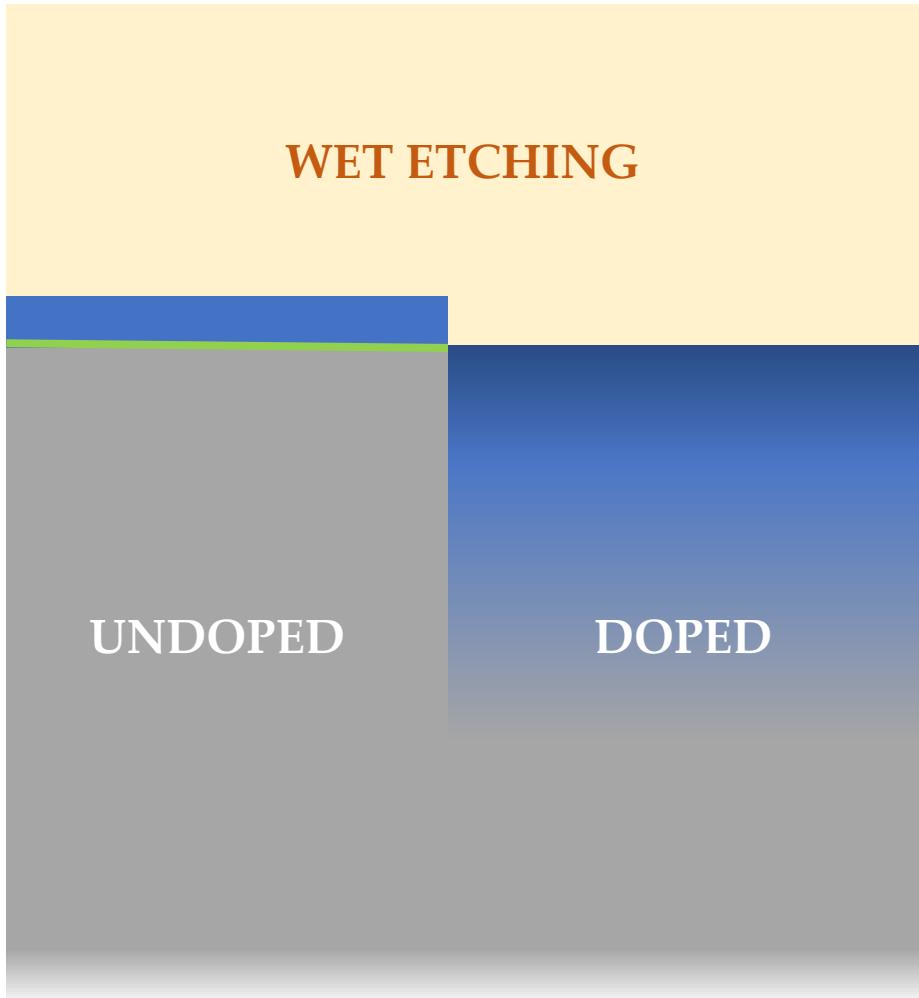
Sb/p-HPGE/Al, L=35mm,
t=2mm



Minimum gap tested 0.1mm



PLM contact/junction: 2° type Segmentation



Full area

PLM

Partial area

Lithographic process using selective etching solutions:

- Hot pure H_2SO_4 for Sb deposition (preserve Sb junction)
- H_2O_2 for GeP deposition (slowly etches everywhere)
- Kern solutions (H_2O_2 , H_3PO_4 , Ethanol) for Al-Ge deposition (preserve Al junction)

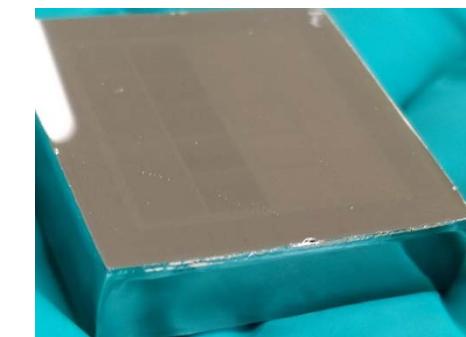
exposure and development,
followed by Au stripping and
resist removal.

Intercontact gaps passivation

(3:1) HNO_3 : HF etching
followed by chemical
quenching passivation.

Selective etching
Removal of untreated dopant
using selective etchants to
protect the near junction.

Chemical passivation
Passivation of undoped
surfaces with suitable solutions.



Thick planar HPGe detectors

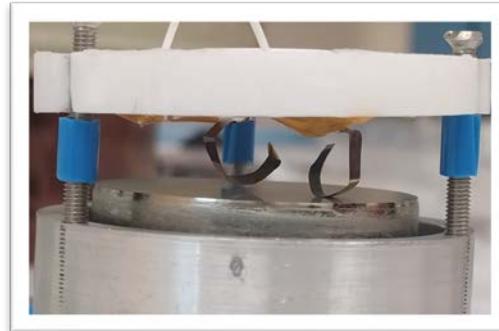


Sb/p-HPGE/Al,
 $L=35\text{mm}$, $t=10\text{mm}$

n+ junction
(spring contact)

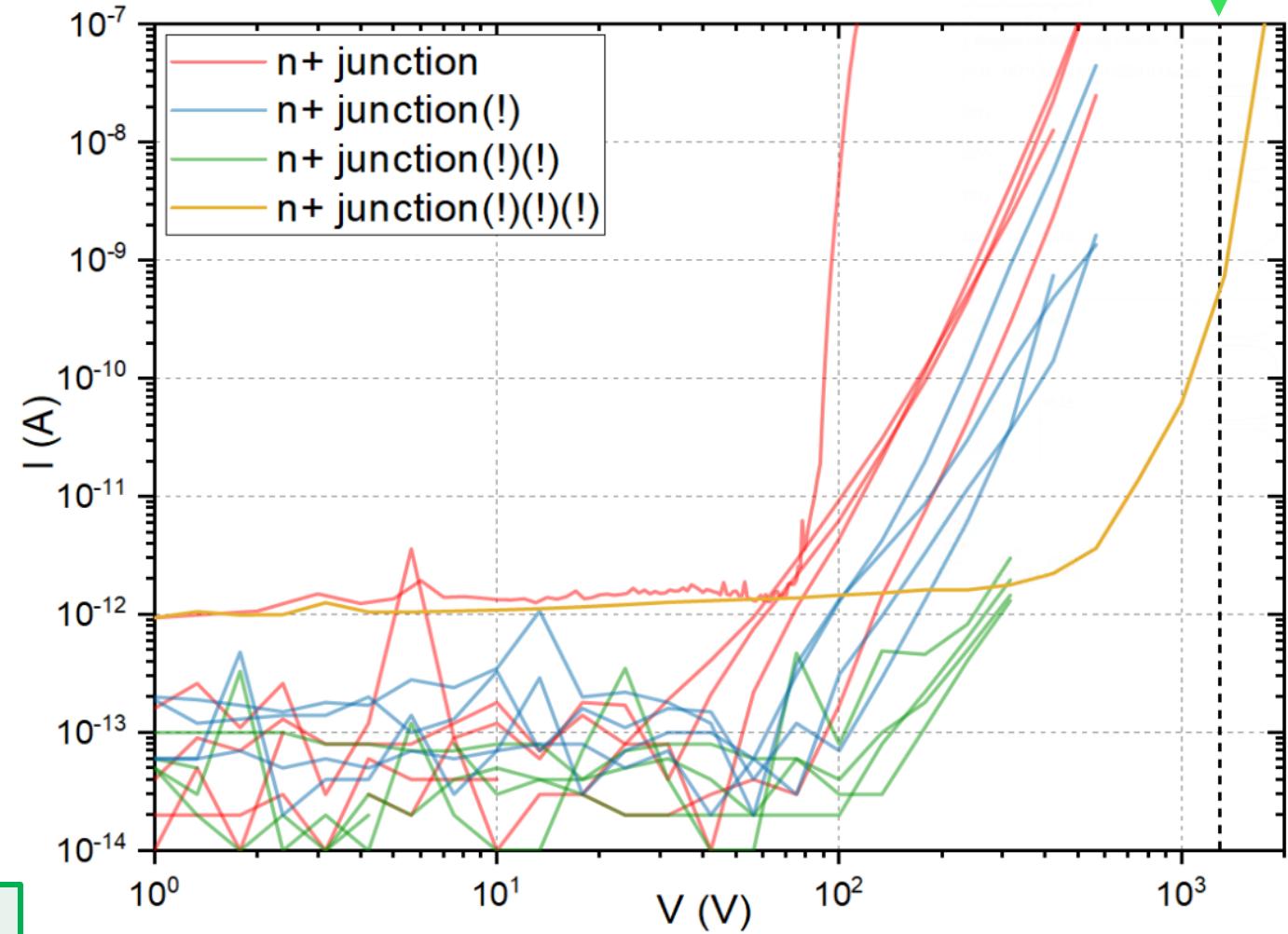


n+ junction (!) / (!) (!)
indium pad



n+ junction (!) (!) (!)
elastic tabs

Sb/p-HPGE/Al,
 $D=40\text{mm}$, $t=20\text{mm}$



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Coaxial HPGe detectors: 3D Photolithography Segmentation

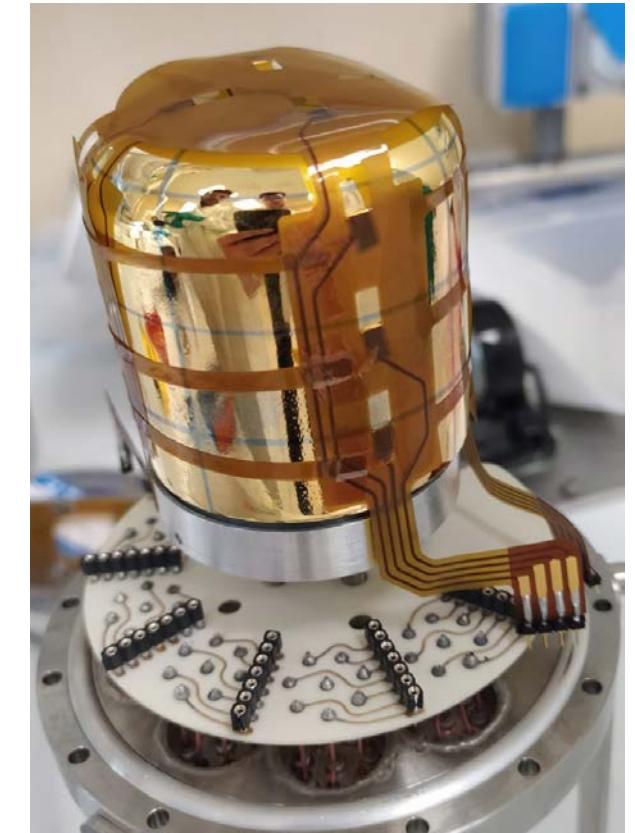
Robot 3D
photolithography



D=50mm, H=50mm



Flexible PCB contacts



Coaxial Photolithography: Robot 3D

The laser micrometer measures the surface after a rotation of the coaxial detector while keeping the robot in the same position

Coaxial Dummy



Misalignment
of the
segmentation
lines at the top
of the sample

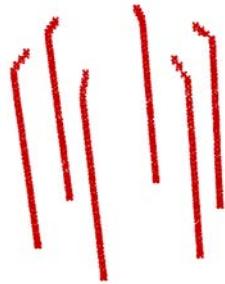
The error is non-reproducible and is caused by the gripping system of the coaxial detector and the hole in the crystal itself

3D mapping of the coaxial detector and obtaining its coordinates relative to the robot's coordinate system with an accuracy of less than 0.1 mm

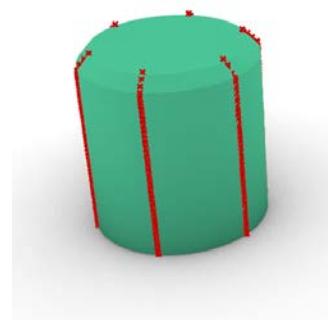


Coaxial Photolithography: Robot 3D

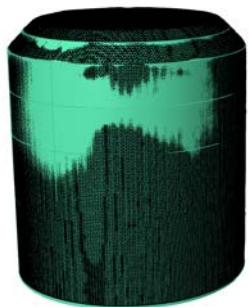
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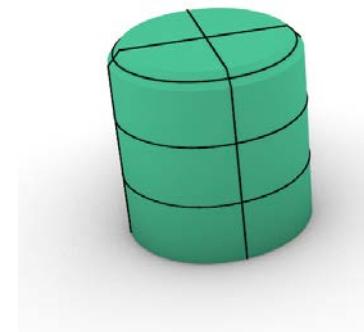
2



3



4



5



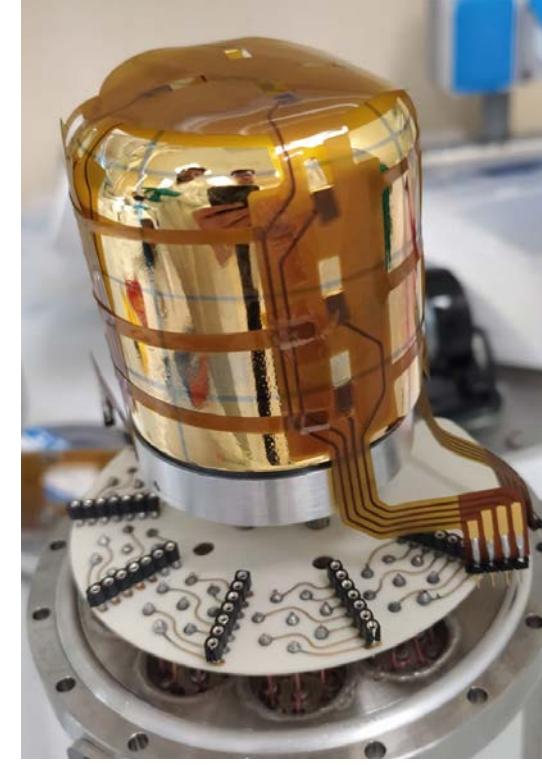
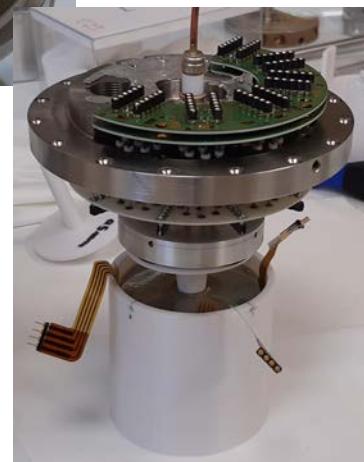
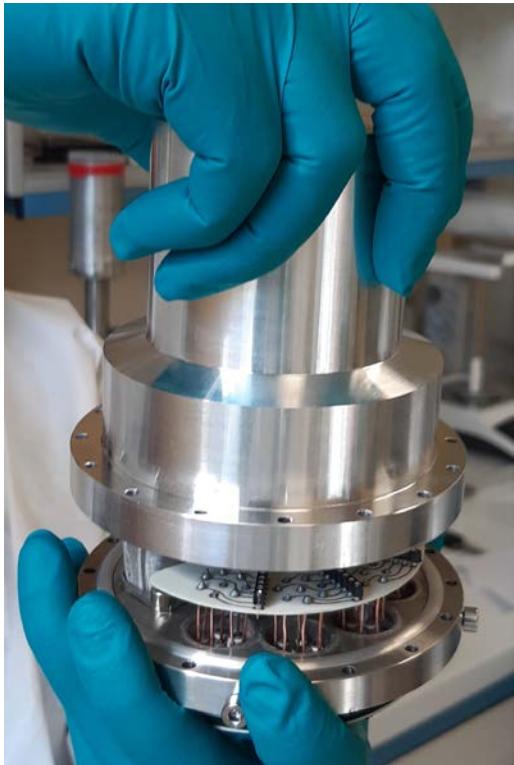
1. Mapping of the cylinder through vertical lines: line formed by a series of points
Each point is determined by the robot's position + laser micrometer measures
2. 3D reconstruction via lofting technique.
3. Comparison with a professional 3D scanner , Accuracy <0.1mm.
4. Construction of the pattern to be lithographed in the robot's coordinate system
5. Photolithography carried out by the robot

UV photolithography robot



Encapsulation of Coaxial detector

Vacuum - tight canister



Flexible Kapton PCB



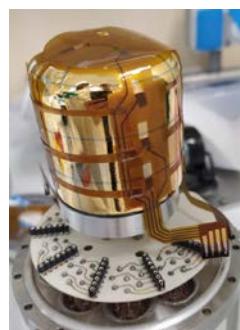
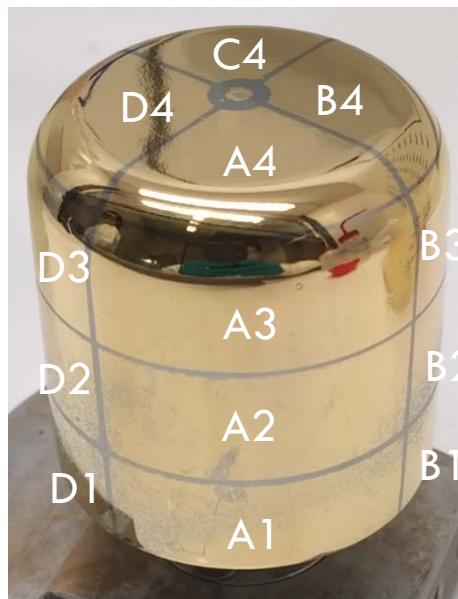
S. Capra et al, JINST 19 C01011 (2024)

Segmentation Test of Coaxial detector

T= 25°C

Ω	A1		B1		C1		D1
A2	17.8	B2	16.6	C2	16.4	D2	22.1
A3	23.6	B3	21.3	C3	21.5	D3	27.3
A4	26.8	B4	23.8	C4	23.6	D4	30.5

Ω	A1		A2		A3		A4
B1	22.5	B2	18.0	B3	17.7	B4	18.0
C1	27.0	C2	19.8	C3	19.4	C4	20.1
D1	21.7	D2	16.3	D3	18.1	D4	17.4



T= 80°K

$G\Omega$	C1	C3	D2	D4
Up	0.4	20	1.4	/
Down	/	0.6	7.5	3.0
Right	6.0	7.7	5.3	31.3
Left	4.3	25.0	0.1	12.8

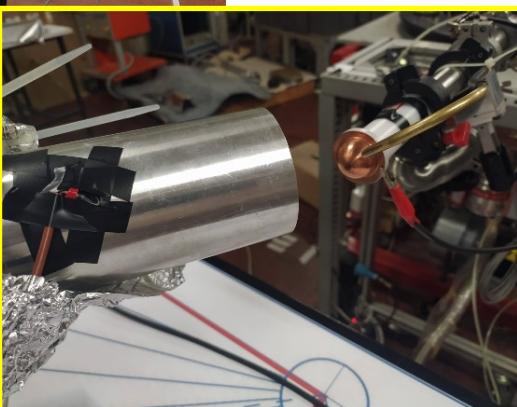
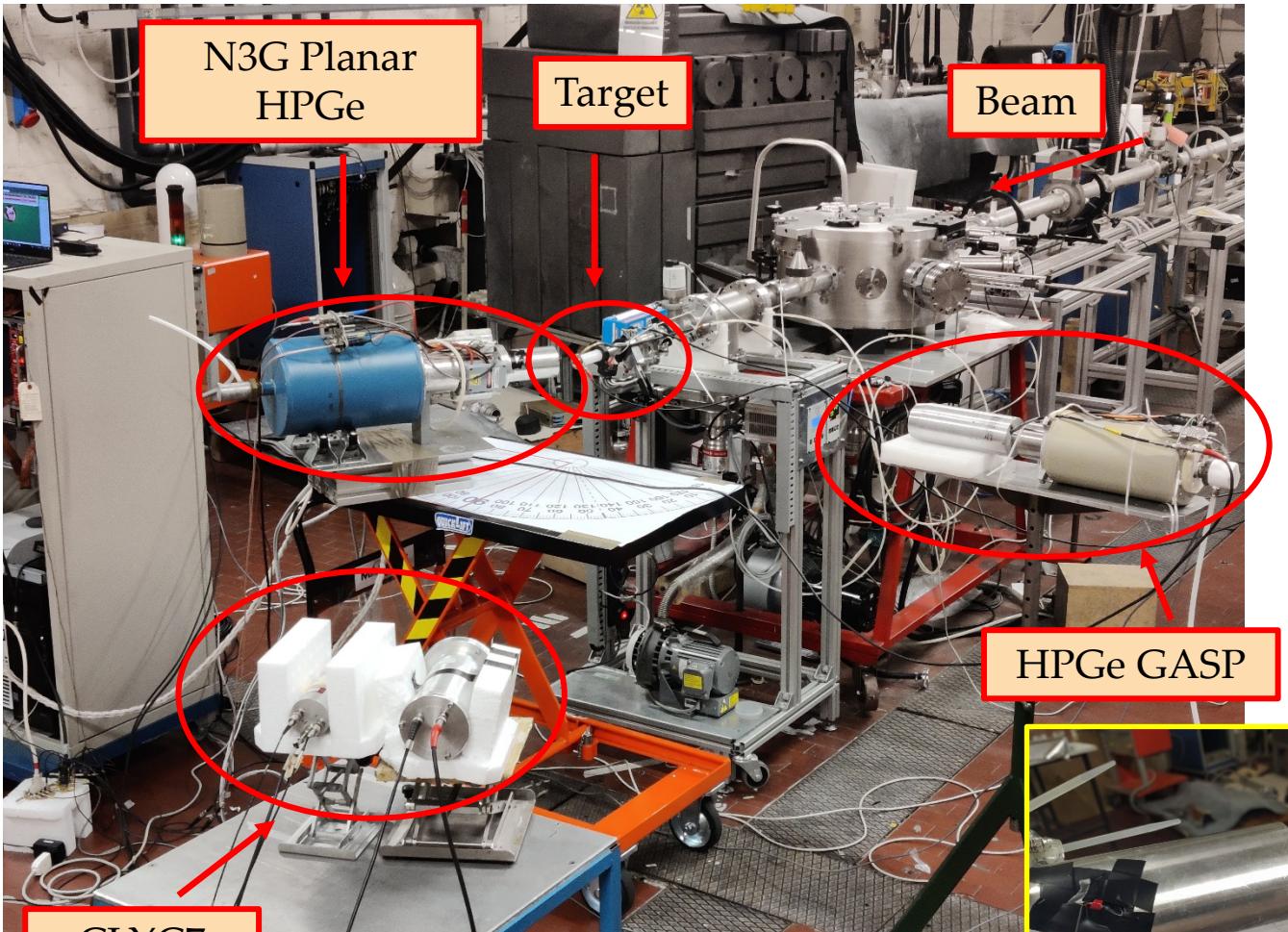
$G\Omega$	A1	B2	B4
Up	8.9	21.7	/
Down	/	3.1	27.8
Right	62.5	0.2	5.0
Left	62.5	11.4	12.5

High resistance between the segments is measured, exceeding 100 M Ω

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Neutrons damage on planar PLM segmented detector



380nA 4MeV proton beam
 ^{7}Li target, 100 μm

Reaction: $^{7}\text{Li} \text{ (p,n)} ^{7}\text{Be}$

Prototype detector is located at 30° 9.5 cm

Neutrons are directly measured with

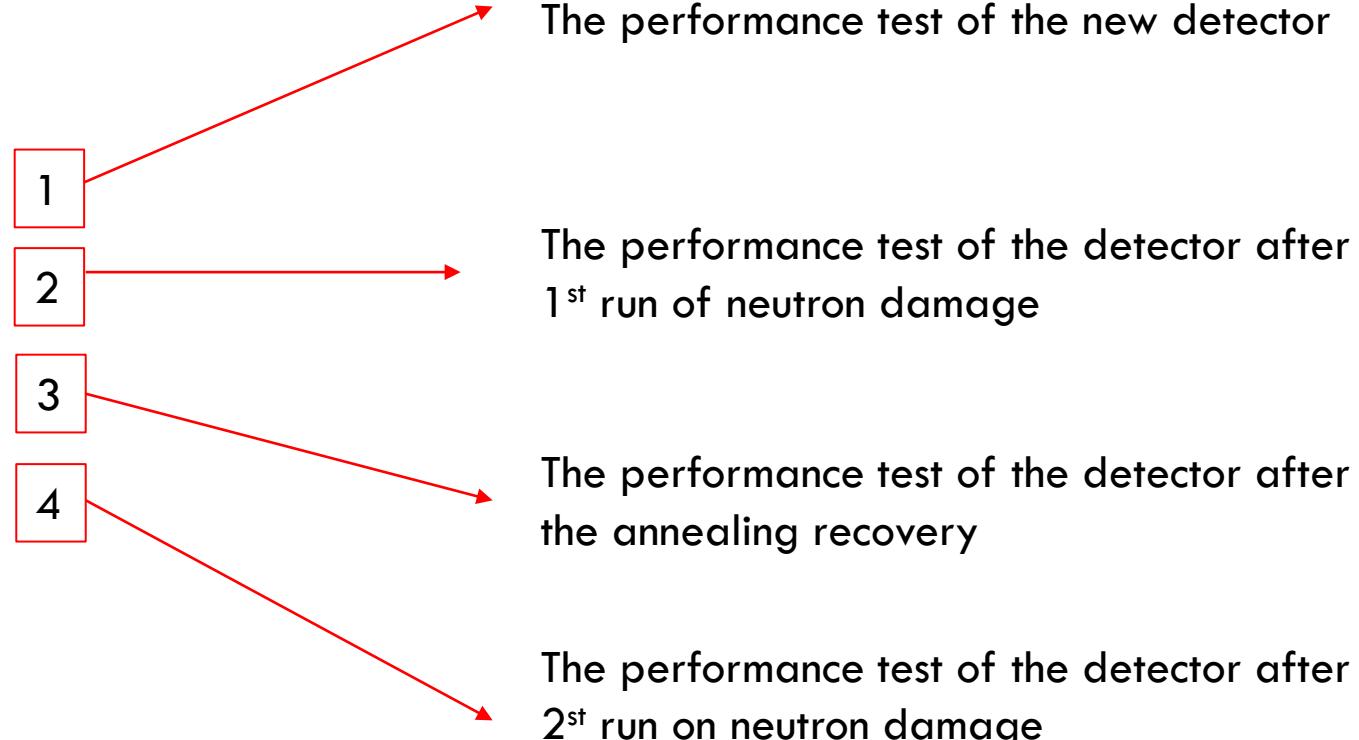
- CLYC7 scintillators, 30° 2 m
- GASP HPGe γ detector, 90° 1 m



R. Escudeiro et all. "Neutron radiation damage on a planar segmented germanium detector" proceeding
Presented at the XXXVII Mazurian Lakes Conference on Physics, Piaski, Poland, September 3-9, 2023

Neutrons damage on planar PLM segmented detector: process steps

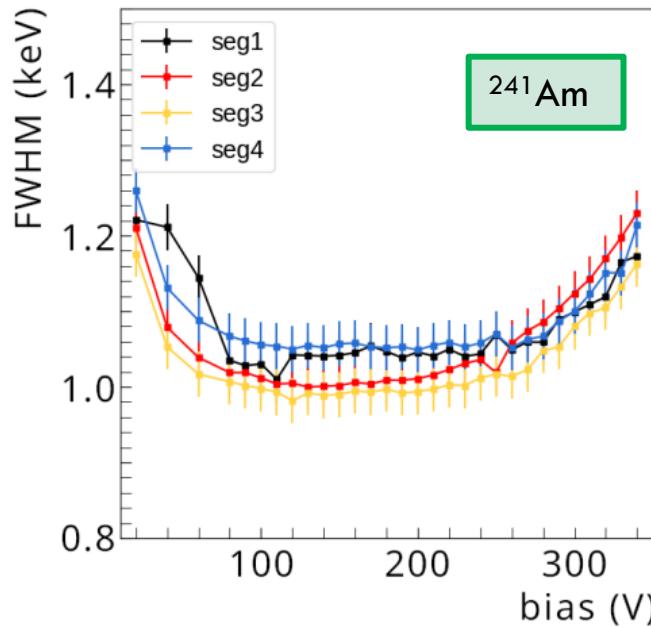
Detector prototype:
Sb/p-HPGE/AI,
 $L = 32\text{mm}$,
 $t = 8.6\text{mm}$
4 contacts + guard ring



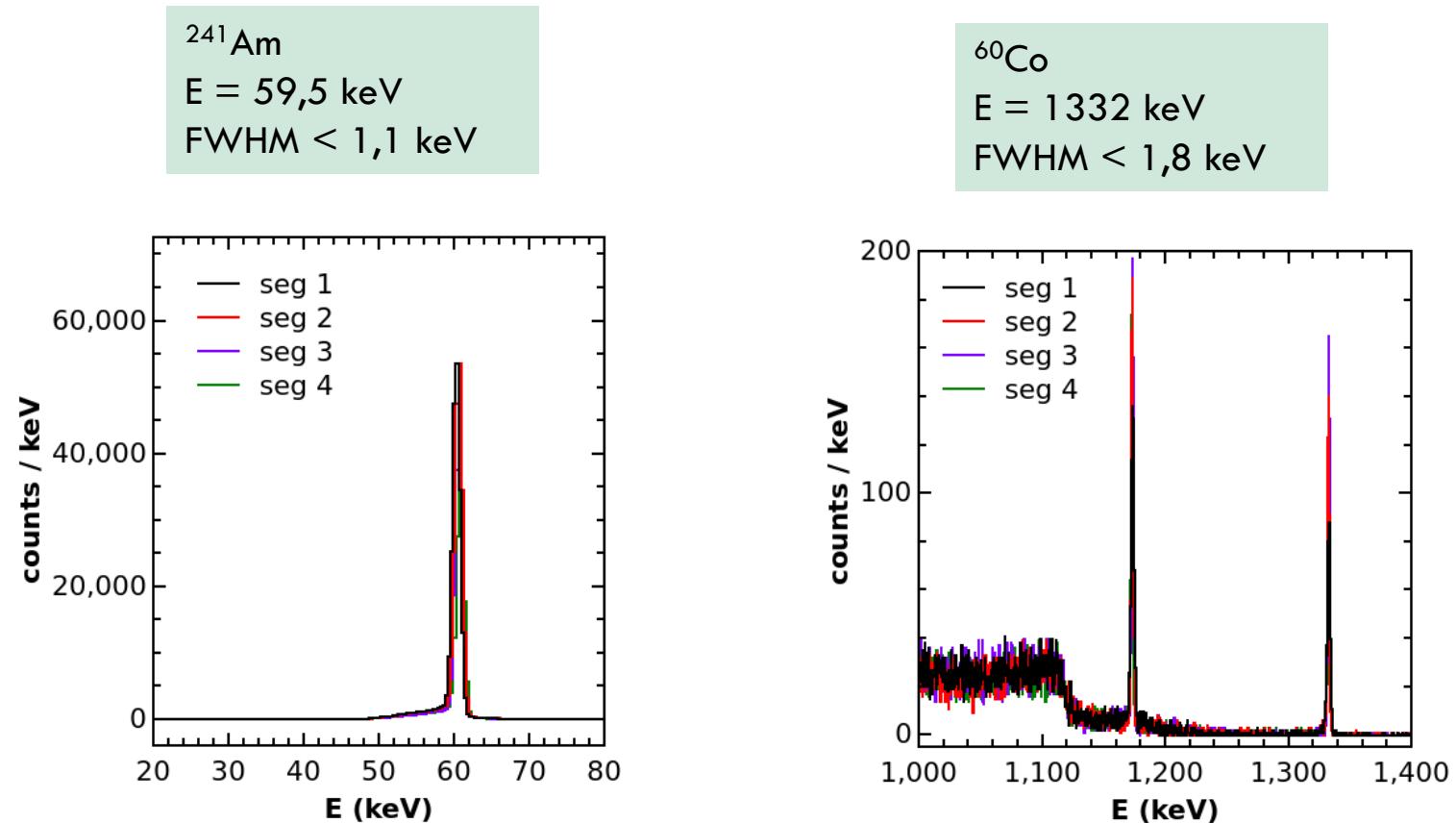
Neutrons damage on planar PLM segmented detector: before run

Detector prototype:
Sb/p-HPGE/Al, L = 32mm, t = 8.6mm
4 contacts + guard ring

Energy resolution in the lab



Starting resolution at 80V operational bias
before the neutron damage run

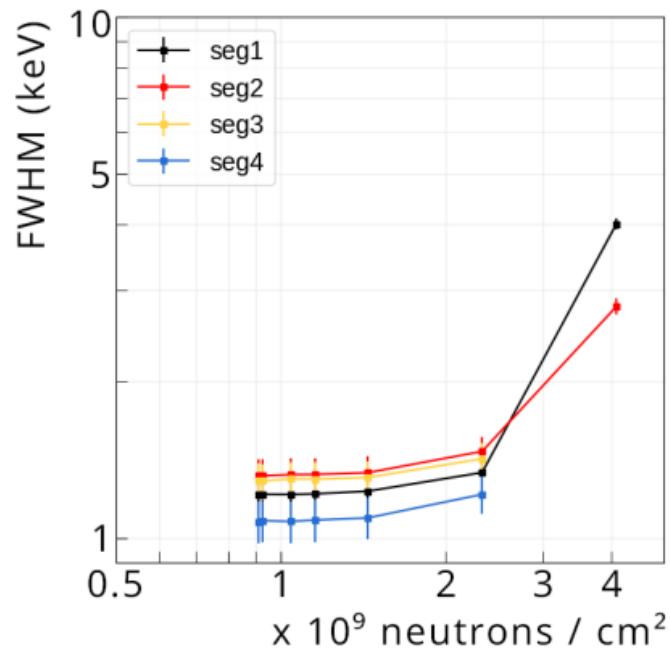


Neutrons damage on planar PLM segmented detector: after 1° run

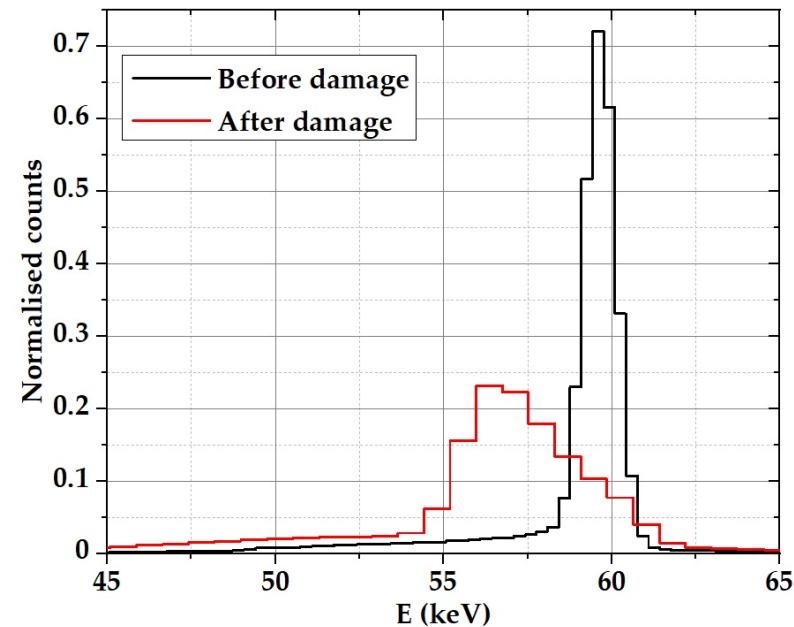
Operational Voltage 80V

Neutron irradiation for increasing time intervals
alternated to 5 min runs with ^{241}Am and ^{60}Co leads
to increasing resolution worsening

After 4 hours of irradiation time,
 $\approx 4 \cdot 10^9$ neutrons/cm², detector is no longer operable



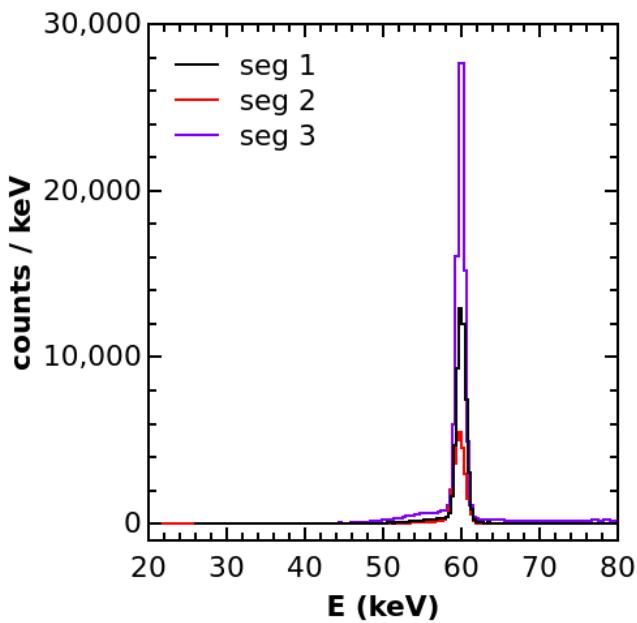
^{241}Am
 $E = 59,5$ keV
FWHM = 3,2 – 4,2 keV



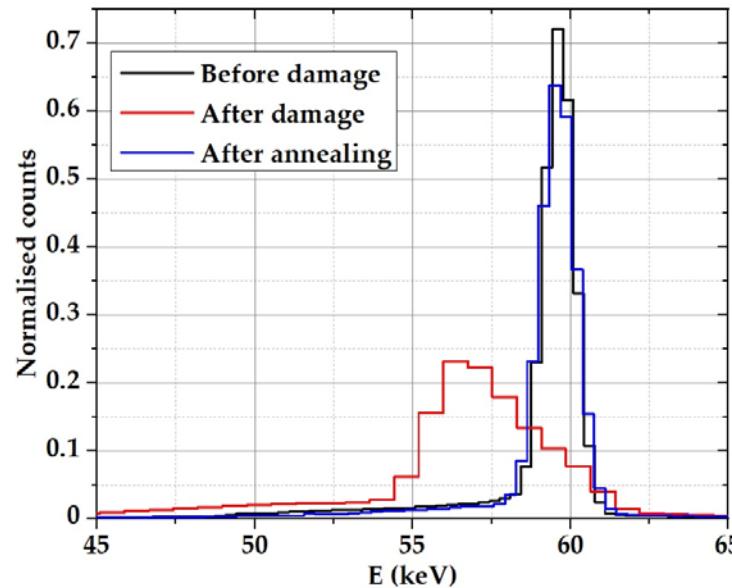
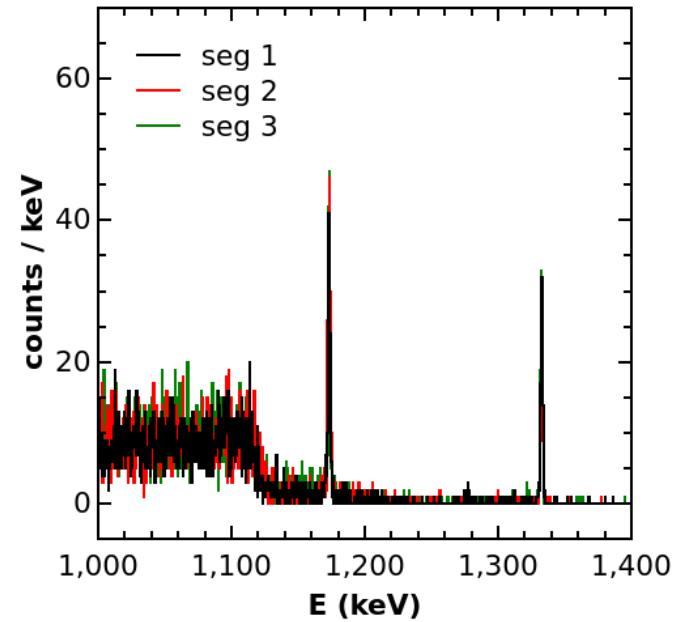
Neutrons damage on planar PLM segmented detector: After Recovery

Annealing procedure: 7 days at 105°C continuously pumped inside the cryostat

^{241}Am
 $E = 59,5 \text{ keV}$
FWHM < 1,6 keV



^{60}Co
 $E = 1332 \text{ keV}$
FWHM < 2 keV



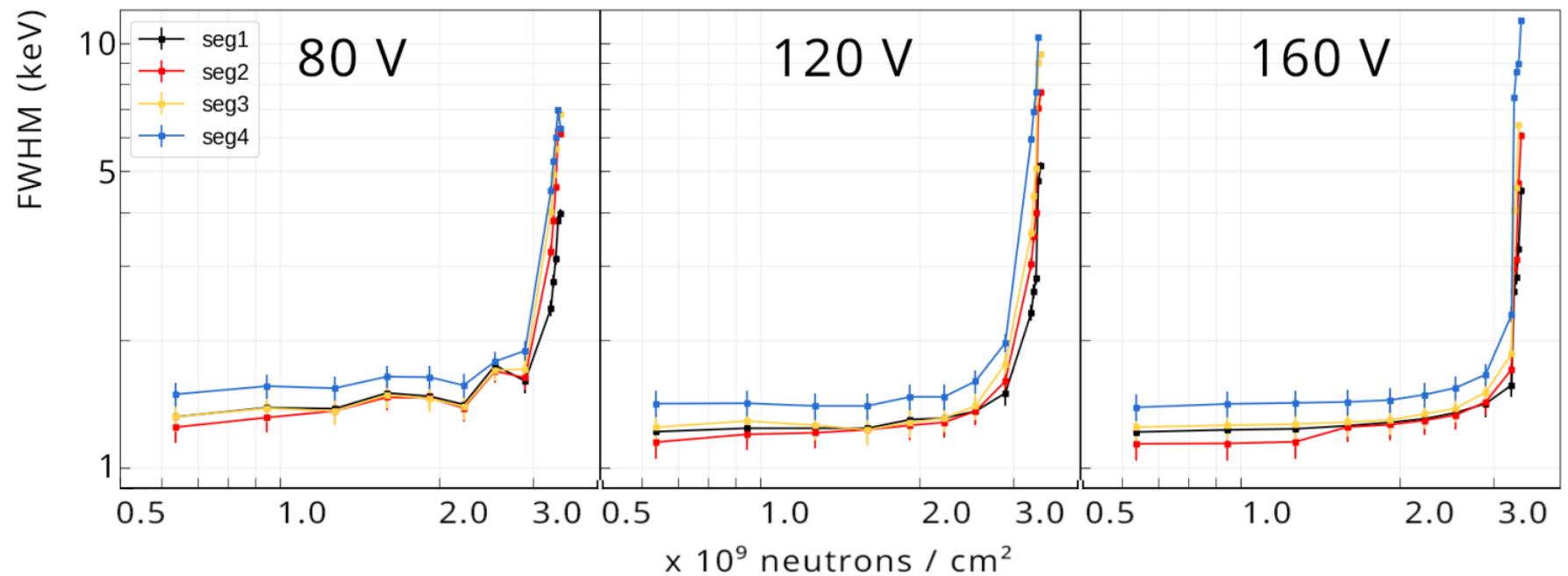
Neutrons damage on planar PLM segmented detector: After 2° run

Operational Voltage 80-120-160V

Neutron irradiation for 20 and 2 min to 5 min runs with
 ^{241}Am to better characterize resolution worsening

Drastic drop in resolution after
 $\approx 3 \cdot 10^9 \text{ neutrons/cm}^2$ irradiation fluence

^{241}Am
 $E = 59,5 \text{ keV}$
FWHM = < 2 keV until
threshold



SUMMARY

- PLM technology can be apply to HPGe crystal (hyperpurity preserve)
- PLM junction is thin, segmentable and termally stable (annealing recovery)
- PLM and segmentation technology can be applied to both planar and coaxial detectors (2D to 3D shape)
- The HPGe crystal surface preparation and the electrical contact force are fundamental
- PLM segmented detector recovers after Neutron damage with a very good energy resolution

R&D Gamma ray detector Team

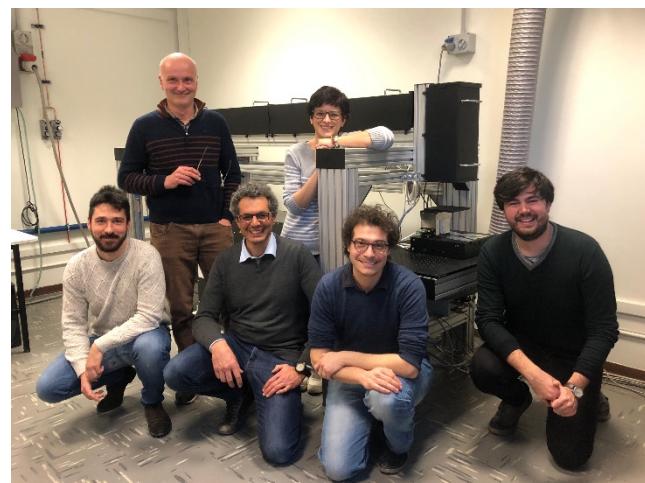
Davide De Salvador
Stefano Bertoldo
Enrico Napolitani
Francesco Sgarbossa

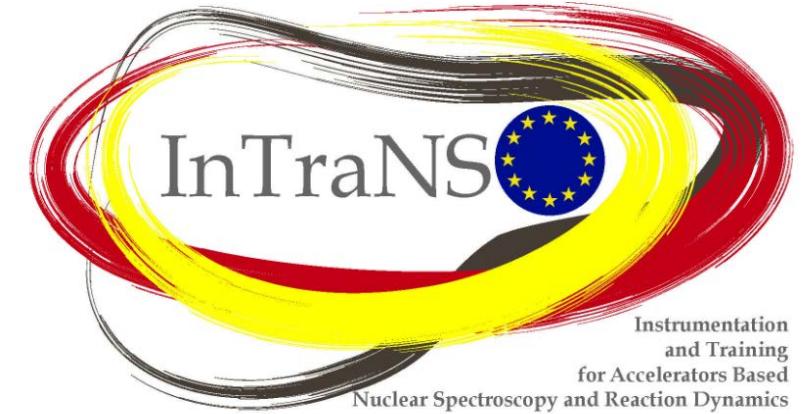
Sara Carturan
Gianluigi Maggioni
Francesco Recchia
Dino Bazzacco

Walter Raniero
Daniel Napoli
Chiara Carraro

Stefano Capra
Giacomo Secci
Alberto Pullia
Bénédicte Million
Luciano Manara

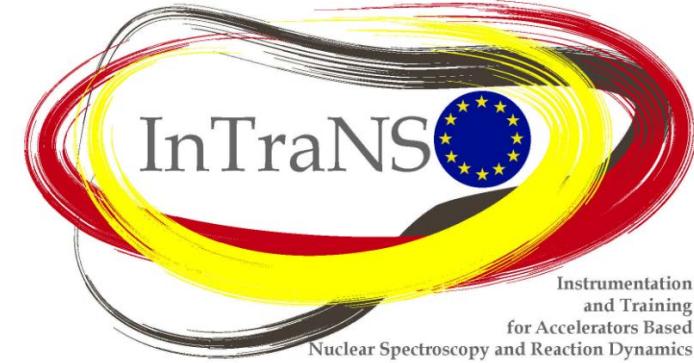
Andrea Mazzolari
Lorenzo Malagutti
Andres Gadea





InTraNS Gamma Detectors Hands-on Training

LNL-INFN (Italy), 2 - 6 of September 2024



Development and test of new technologies for manufacturing high purity germanium segmented detector

Walter Raniero
INFN – LNL

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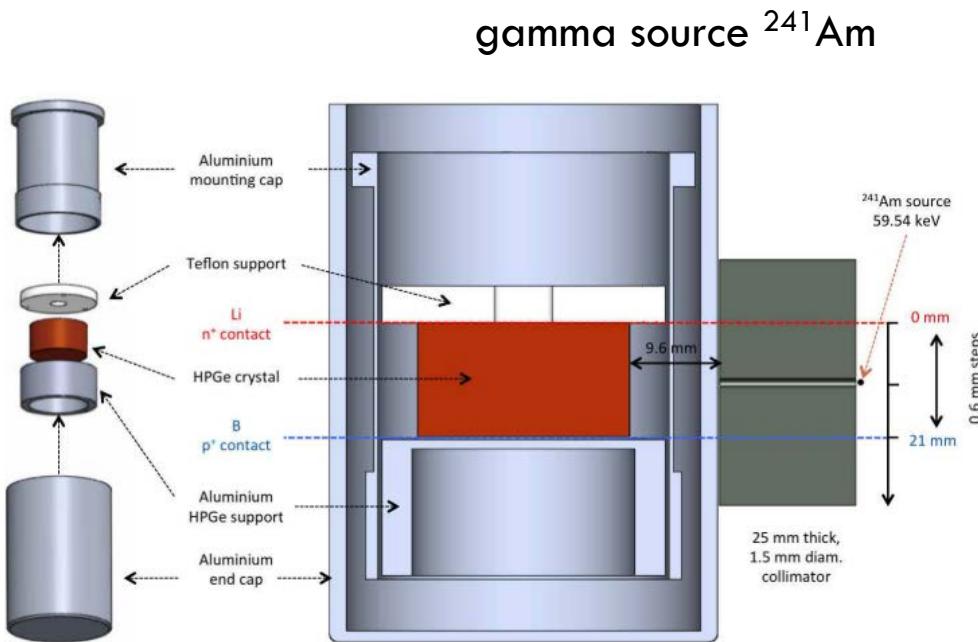


Germanium material for gamma detector (passivation γ -ray scanning)

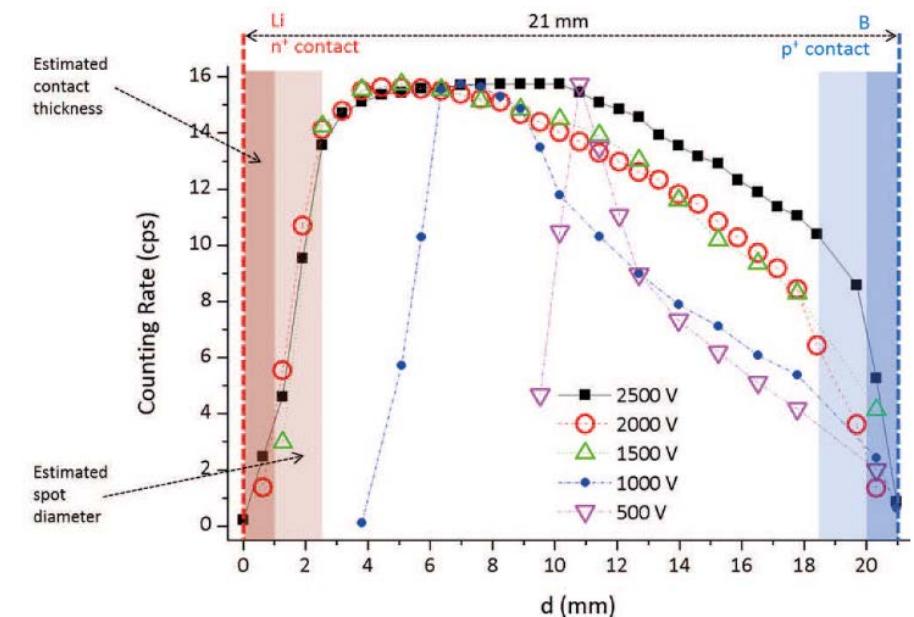
HPGe Passivation: lateral scan ^{241}Am on passivated surface



Cryogenic cryostat
 $80 \div 90\text{K}$



Depletion Voltage

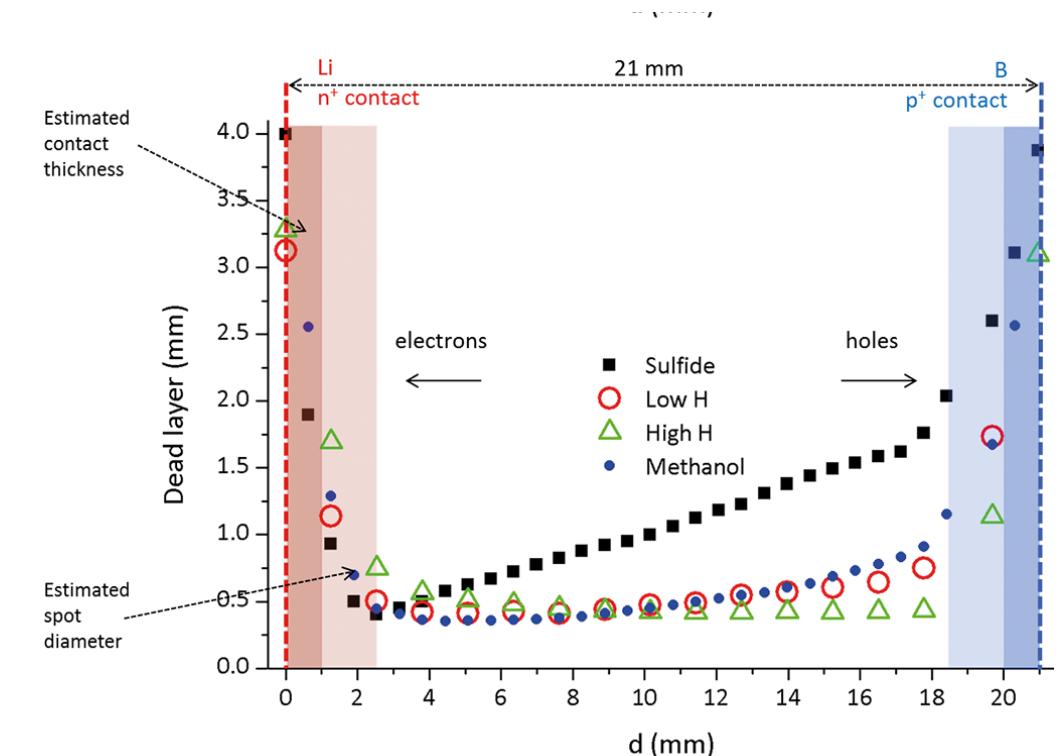
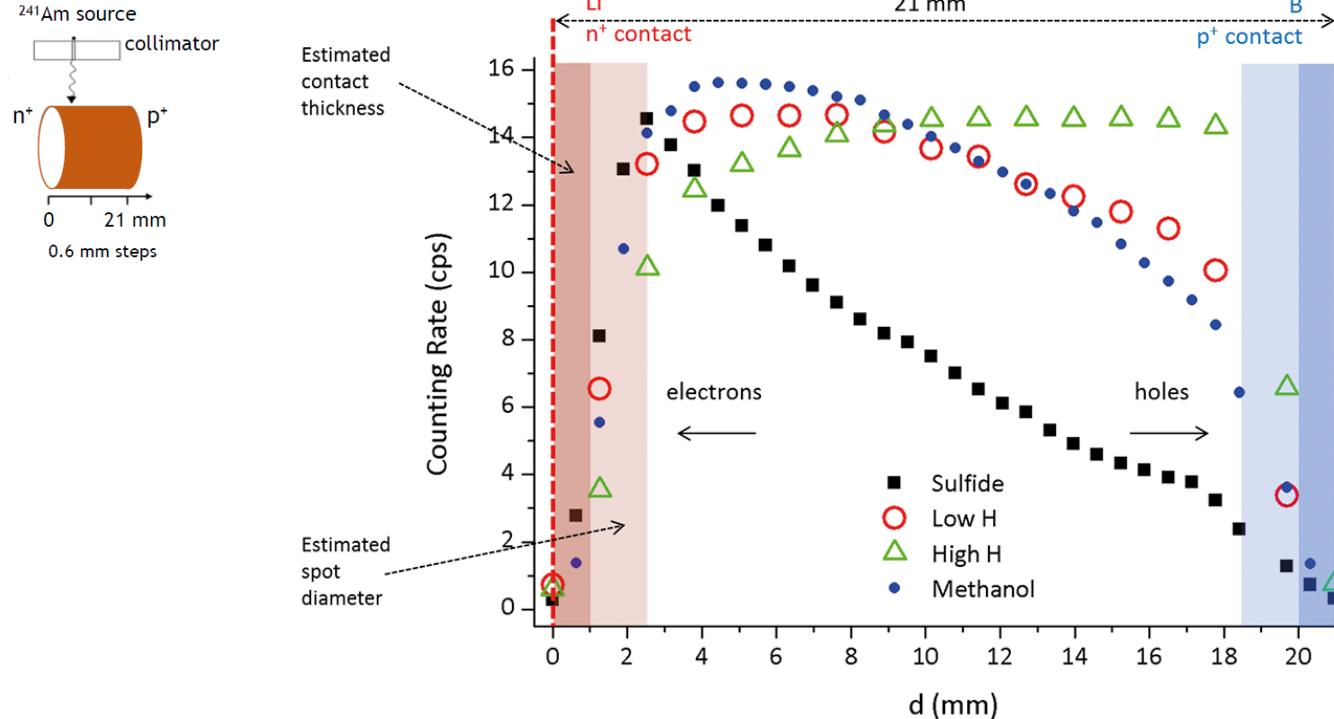


Counting rate (59.5 keV) of the methanol-passivated detector, at different voltage apply

G. Maggioni et al. *Eur. Phys. J. A* (2015) 51: 141

Germanium material for gamma detector (passivation γ -ray scanning)

HPGe Passivation: lateral scan ^{241}Am on passivated surface



- Methanol termination
- Sulphide termination
- Low Hydride termination (10% HF)
- High Hydride termination (50% HF)

G. Maggioni et al. Eur. Phys. J. A (2015) 51: 141

Thin dead layer on passivation surface

HPGe gamma detector (*chemical Passivation*)

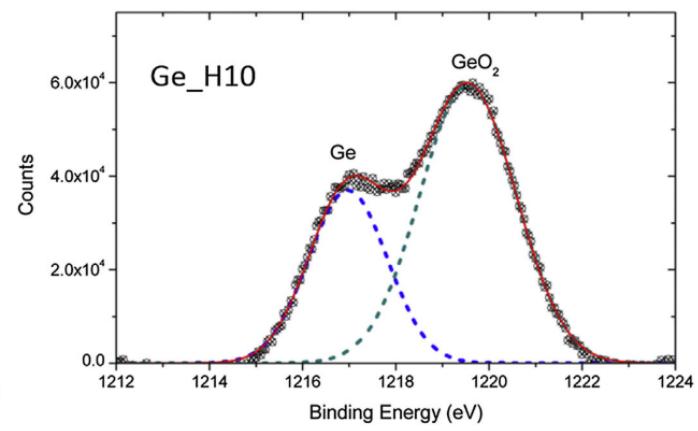
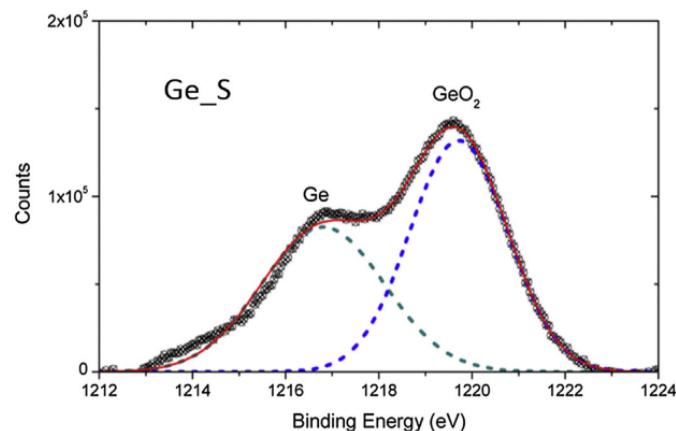
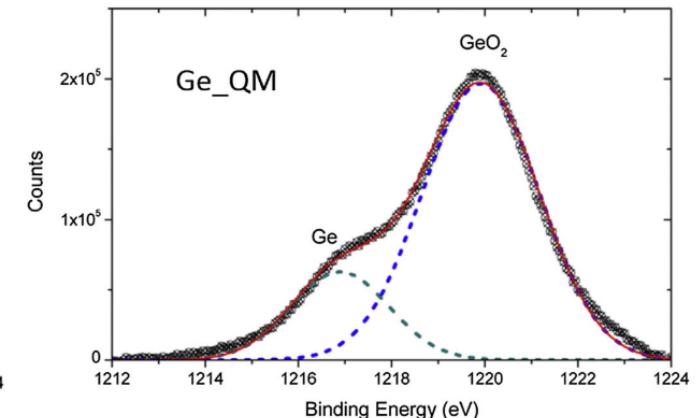
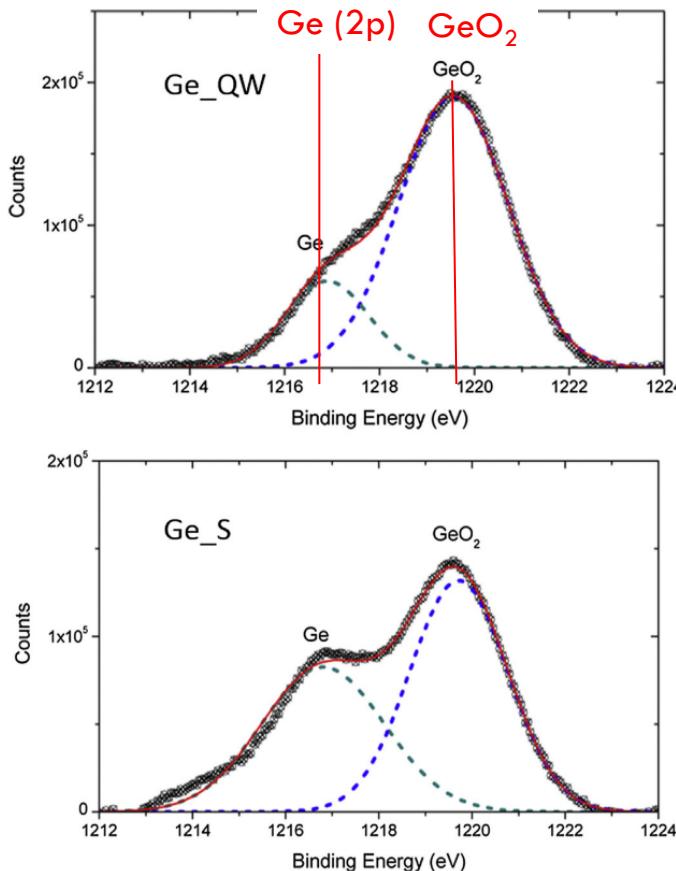
Passivation techniques: study the evolution
of Ge – GeO – GeO₂

Lateral
surface
passivated



XPS Binding Energy collected after 1
month of air exposure (RH about 55%)

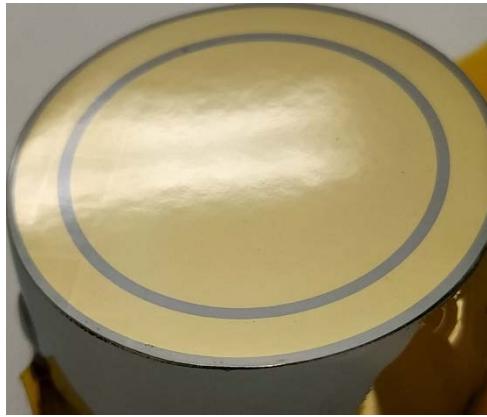
X-ray Photoelectron Spectroscopy (XPS)



S. Carturan et al., *Mater. Chem. Phys.* 2015

Thick planar HPGe detectors

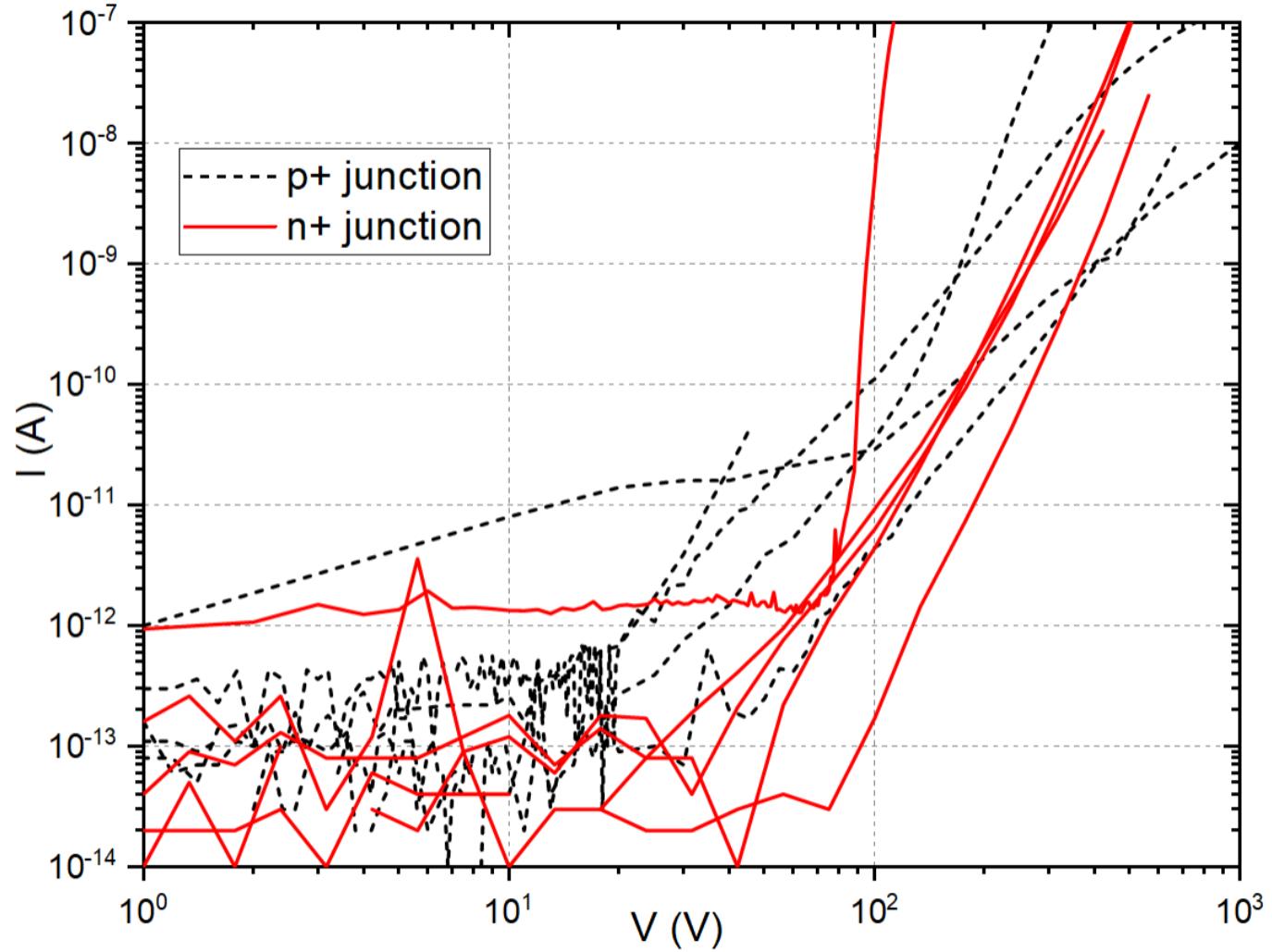
Al/n-HPGE/Sb,
D=40mm, t=20mm



Sb/p-HPGE/Al,
L=35mm, t=10mm



P/p-HPGE/Al, L=35mm,
t=10mm



Thick planar HPGe detectors

Al/n-HPGE/Sb,
D=40mm, t=20mm



Sb/p-HPGE/Al,
L=35mm, t=10mm



P/p-HPGE/Al,
L=35mm, t=10mm



Difficult to reach
depletion voltages
(600V for 1cm,
2200V for 2 cm)

Probably due to
junction mechanical
weakness under
manipulation

